RF Test Report

For

Applicant Name:	**SHENZHEN YUNJI INTELLIGENT TECHNOLOGY CO.,LTD**
Address:	A2 2F BUILDNG ENET NEW INDUSTRIAL PARK, DAFU INDUSTRIAL ZONE, GUANLAN, LONGHUA SHENZHEN, 518XXX China
EUT Name:	Smart Phone
Brand Name:	OUKITEL
Model Number:	C57
Series model number	C57 S,C57 Pro,C57 Plus,C57 Ultra

Issued By

Company Name:	**BTF Testing Lab (Shenzhen) Co., Ltd.**
Address:	F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China
Report Number:	BTF240729R00901
Test Standards:	47 CFR Part 15.247
Test Conclusion:	Pass
FCC ID:	2ANMU-C57
Test Date:	2024-07-30 to 2024-08-22
Date of Issue:	2024-08-22
Test By:	Ssxx.guo/ Tester
Prepared By:	Ace Xie / Project Engineer
Date:	2024-08-22
Approved By:	Ryan.CJ / EMC Manager
Date:	2024-08-22

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Revision History		
Version	Issue Date	Revisions Content
R_V0	2024-08-22	Original
Note: Once the revision has been made, then previous versions reports are invalid.		

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1 Introduction

1.1 Identification of Testing Laboratory

Company Name:	BTF Testing Lab (Shenzhen) Co., Ltd.
Address:	F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China
Phone Number:	+86-0755-23146130
Fax Number:	+86-0755-23146130

1.2 Identification of the Responsible Testing Location

Company Name:	BTF Testing Lab (Shenzhen) Co., Ltd.
Address:	F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China
Phone Number:	+86-0755-23146130
Fax Number:	+86-0755-23146130
FCC Registration Number:	518915
Designation Number:	CN1330

1.3 Announcement

(1) The test report reference to the report template version v0.
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(3) The test report is invalid if there is any evidence and/or falsification.
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2 Product Information

2.1 Application Information

Company Name:	SHENZHEN YUNJI INTELLIGENT TECHNOLOGY CO.,LTD
Address:	A2 2F BUILDNG ENET NEW INDUSTRIAL PARK, DAFU INDUSTRIAL ZONE, GUANLAN, LONGHUA SHENZHEN, 518XXX China

2.2 Manufacturer Information

Company Name:	SHENZHEN YUNJI INTELLIGENT TECHNOLOGY CO.,LTD
Address:	A2 2F BUILDNG ENET NEW INDUSTRIAL PARK, DAFU INDUSTRIAL ZONE, GUANLAN, LONGHUA SHENZHEN, 518XXX China

2.3 Factory Information

Company Name:	SHENZHEN YUNJI INTELLIGENT TECHNOLOGY CO.,LTD
Address:	A2 2F BUILDNG ENET NEW INDUSTRIAL PARK, DAFU INDUSTRIAL ZONE, GUANLAN, LONGHUA SHENZHEN, 518XXX China

2.4 General Description of Equipment under Test (EUT)

EUT Name:	Smart Phone
Test Model Number:	C57
Series model name	C57 S,C57 Pro,C57 Plus,C57 Ultra
Description of model name differentiation	Only the model name is different, the others are the same.

2.5 Technical Information

Power Supply:	DC 5V from adaptor or DC 4.4V from battery
Power Adaptor:	Model:ZFX021 Input:100-240V, 50/60Hz 0.2A Output:DC5.0V 1000mA
Operation Frequency:	2402MHz to 2480MHz
Number of Channels:	79
Modulation Type:	GFSK, π/4 DQPSK, 8DPSK
Antenna Type:	PIFA Antenna
Antenna Gain#:	0.65 dBi
Note: #: The antenna gain provided by the applicant, and the laboratory will not be responsible for the accumulated calculation results which covers the information provided by the applicant.	

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3 Summary of Test Results

3.1 Test Standards

The tests were performed according to following standards:
47 CFR Part 15.247: Operation within the bands 902-928 MHz, 2400-2483.5 MHz, and 5725-5850 MHz

3.2 Uncertainty of Test

Item	Measurement Uncertainty
Conducted Emission (150 kHz-30 MHz)	±2.64dB
Occupied Bandwidth	±69kHz
Transmitter Power, Conducted	±0.87dB
Conducted Spurious Emissions	±0.95dB
Radiated Spurious Emissions (above 1GHz)	1-6GHz: ±3.94dB 6-18GHz: ±4.16dB
Radiated Spurious Emissions (30M - 1GHz)	±4.12dB
The following measurement uncertainty levels have been estimated for tests performed on the EUT as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.	

3.3 Summary of Test Result

Item	Standard	Requirement	Result
Antenna requirement	47 CFR Part 15.247	47 CFR 15.203	Pass
Conducted Emission at AC power line	47 CFR Part 15.247	47 CFR 15.207(a)	Pass
Occupied Bandwidth	47 CFR Part 15.247	47 CFR 15.215(c)	Pass
Maximum Conducted Output Power	47 CFR Part 15.247	47 CFR 15.247(b)(1)	Pass
Channel Separation	47 CFR Part 15.247	47 CFR 15.247(a)(1)	Pass
Number of Hopping Frequencies	47 CFR Part 15.247	47 CFR 15.247(a)(1)(iii)	Pass
Dwell Time	47 CFR Part 15.247	47 CFR 15.247(a)(1)(iii)	Pass
Emissions in non-restricted frequency bands	47 CFR Part 15.247	47 CFR 15.247(d), 15.209, 15.205	Pass
Band edge emissions (Radiated)	47 CFR Part 15.247	47 CFR 15.247(d), 15.209, 15.205	Pass
Emissions in frequency bands (below 1GHz)	47 CFR Part 15.247	47 CFR 15.247(d), 15.209, 15.205	Pass
Emissions in frequency bands (above 1GHz)	47 CFR Part 15.247	47 CFR 15.247(d), 15.209, 15.205	Pass

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4 Test Configuration

4.1 Test Equipment List

Conducted Emission at AC power line					
Equipment	**Manufacturer**	**Model No**	**Inventory No**	**Cal Date**	**Cal Due Date**
Pulse Limiter	SCHWARZBECK	VTSD 9561-F	00953	2023-11-13	2024-11-12
Coaxial Switcher	SCHWARZBECK	CX210	CX210	2023-11-13	2024-11-12
V-LISN	SCHWARZBECK	NSLK 8127	01073	2023-11-16	2024-11-15
LISN	AFJ	LS16/110VAC	16010020076	2023-11-16	2024-11-15
EMI Receiver	ROHDE&SCHWARZ	ESCI3	101422	2023-11-15	2024-11-14

Occupied Bandwidth Maximum Conducted Output Power Channel Separation Number of Hopping Frequencies Dwell Time Emissions in non-restricted frequency bands					
Equipment	**Manufacturer**	**Model No**	**Inventory No**	**Cal Date**	**Cal Due Date**
RFTest software	/	V1.00	/	/	/
RF Control Unit	Techy	TR1029-1	/	2023-11-13	2024-11-12
RF Sensor Unit	Techy	TR1029-2	/	2023-11-13	2024-11-12
Programmable constant temperature and humidity box	ZZCKONG	ZZ-K02A	20210928007	2023-11-16	2024-11-15
Adjustable Direct Current Regulated Power Supply	Dongguan Tongmen Electronic Technology Co., LTD	etm-6050c	20211026123	2023-11-13	2024-11-12
WIDEBAND RADIO COMMNUNICATION TESTER	Rohde & Schwarz	CMW500	161997	2023-11-16	2024-11-15
MXA Signal Analyzer	KEYSIGHT	N9020A	MY50410020	2023-11-16	2024-11-15

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Band edge emissions (Radiated) Emissions in frequency bands (below 1GHz) Emissions in frequency bands (above 1GHz)					
Equipment	**Manufacturer**	**Model No**	**Inventory No**	**Cal Date**	**Cal Due Date**
Coaxial cable Multiflex 141	Schwarzbeck	N/SMA 0.5m	517386	2023-11-13	2024-11-12
Preamplifier	SCHWARZBECK	BBV9744	00246	2023-11-13	2024-11-12
RE Cable	REBES Talent	UF1-SMASMAM-10m	21101566	2023-11-13	2024-11-12
RE Cable	REBES Talent	UF2-NMNM-10m	21101570	2023-11-13	2024-11-12
RE Cable	REBES Talent	UF1-SMASMAM-1m	21101568	2023-11-13	2024-11-12
RE Cable	REBES Talent	UF2-NMNM-1m	21101576	2023-11-13	2024-11-12
RE Cable	REBES Talent	UF2-NMNM-2.5m	21101573	2023-11-13	2024-11-12
POSITIONAL CONTROLLER	SKET	PCI-GPIB	/	2023-11-13	2024-11-12
Horn Antenna	SCHWARZBECK	BBHA9170	01157	2023-11-13	2024-11-12
EMI TEST RECEIVER	ROHDE&SCHWARZ	ESCI7	101032	2023-11-16	2024-11-15
SIGNAL ANALYZER	ROHDE&SCHWARZ	FSQ40	100010	2023-11-16	2024-11-15
POSITIONAL CONTROLLER	SKET	PCI-GPIB	/	2023-11-13	2024-11-12
Broadband Preamplilifier	SCHWARZBECK	BBV9718D	00008	2023-11-16	2024-11-15
Horn Antenna	SCHWARZBECK	BBHA9120D	2597	2023-11-16	2024-11-15
EZ_EMC	Frad	FA-03A2 RE+	/	/	/
POSITIONAL CONTROLLER	SKET	PCI-GPIB	/	2023-11-13	2024-11-12
Log periodic antenna	SCHWARZBECK	VULB 9168	01328	2023-11-13	2024-11-12

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4.2 Test Auxiliary Equipment

The EUT was tested as an independent device.

4.3 Test Modes

No.	Test Modes	Description
TM1	TX-GFSK (Non-Hopping)	Keep the EUT in continuously transmitting mode (non-hopping) with GFSK modulation.
TM2	TX-Pi/4DQPSK (Non-Hopping)	Keep the EUT in continuously transmitting mode (non-hopping) with Pi/4DQPSK modulation.
TM3	TX-8DPSK (Non-Hopping)	Keep the EUT in continuously transmitting mode (non-hopping) with 8DPSK modulation.
TM4	TX-GFSK (Hopping)	Keep the EUT in continuously transmitting mode (hopping) with GFSK modulation,.
TM5	TX-Pi/4DQPSK (Hopping)	Keep the EUT in continuously transmitting mode (hopping) with Pi/4DQPSK modulation.
TM6	TX-8DPSK (Hopping)	Keep the EUT in continuously transmitting mode (hopping) with 8DPSK modulation.

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5 Evaluation Results (Evaluation)

5.1 Antenna requirement

Test Requirement:	Refer to 47 CFR Part 15.203, an intentional radiator shall be designed to ensure that no antenna other than that furnished by the responsible party shall be used with the device. The use of a permanently attached antenna or of an antenna that uses a unique coupling to the intentional radiator shall be considered sufficient to comply with the provisions of this section.

5.1.1 Conclusion:

6 Radio Spectrum Matter Test Results (RF)

6.1 Conducted Emission at AC power line

Test Requirement:	Refer to 47 CFR 15.207(a), Except as shown in paragraphs (b)and (c)of this section, for an intentional radiator that is designed to be connected to the public utility (AC) power line, the radio frequency voltage that is conducted back onto the AC power line on any frequency or frequencies, within the band 150 kHz to 30 MHz, shall not exceed the limits in the following table, as measured using a 50 μH/50 ohms line impedance stabilization network (LISN).
Test Method:	ANSI C63.10-2013 section 6.2
Test Limit:	

Frequency of emission (MHz)	Conducted limit (dBμV)	
	Quasi-peak	Average
0.15-0.5	66 to 56*	56 to 46*
0.5-5	56	46
5-30	60	50

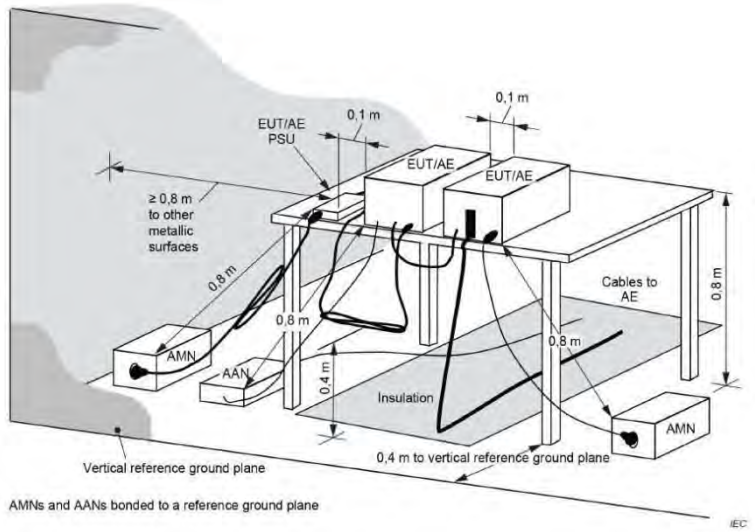
*Decreases with the logarithm of the frequency.

Procedure:	Refer to ANSI C63.10-2013 section 6.2, standard test method for ac power-line conducted emissions from unlicensed wireless devices

6.1.1 E.U.T. Operation:

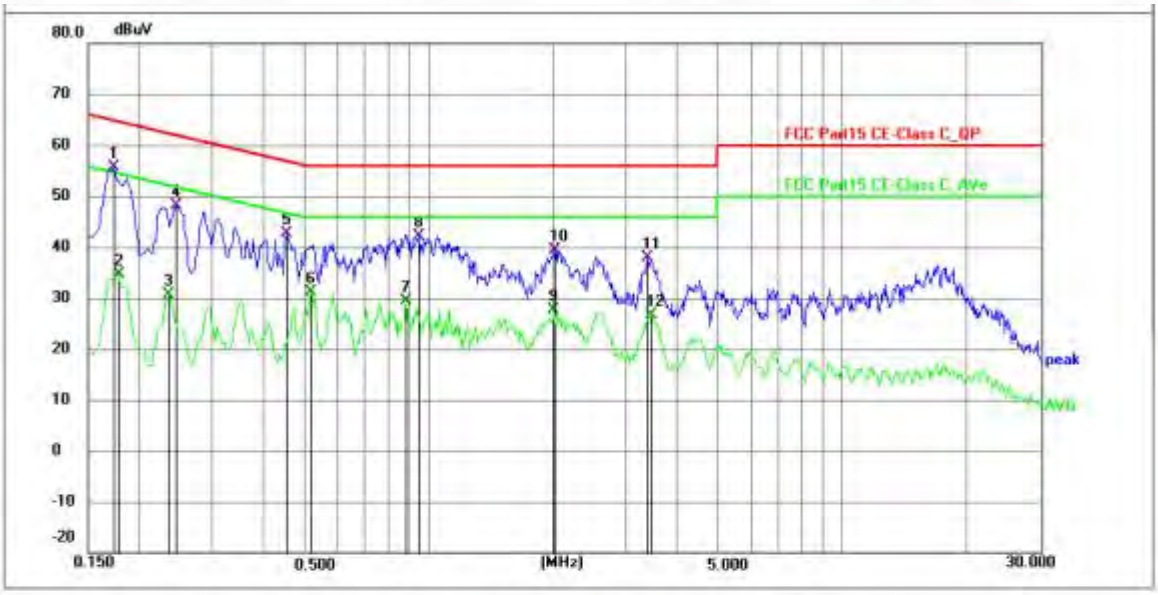
Operating Environment:	
Temperature:	24.7 °C
Humidity:	52 %
Atmospheric Pressure:	1010 mbar

6.1.2 Test Setup Diagram:



6.1.3 Test Data:

TM1 / Line: Line / Band: 2400-2483.5 MHz / BW: 1 / CH: M



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB)	Level (dBuV)	Limit (dBuV)	Margin (dB)	Detector	P/F	Remark
1 *	0.1723	45.02	10.49	55.51	64.85	-9.34	QP	P	
2	0.1770	24.02	10.51	34.53	54.63	-20.10	AVG	P	
3	0.2353	20.18	10.56	30.74	52.26	-21.52	AVG	P	
4	0.2444	37.66	10.56	48.22	61.95	-13.73	QP	P	
5	0.4515	32.05	10.57	42.62	56.85	-14.23	QP	P	
6	0.5190	20.49	10.59	31.08	46.00	-14.92	AVG	P	
7	0.8832	18.76	10.68	29.44	46.00	-16.56	AVG	P	
8	0.9465	31.40	10.67	42.07	56.00	-13.93	QP	P	
9	2.0040	17.05	10.68	27.73	46.00	-18.27	AVG	P	
10	2.0220	28.65	10.68	39.33	56.00	-16.67	QP	P	
11	3.3720	27.18	10.64	37.82	56.00	-18.18	QP	P	
12	3.4394	16.06	10.64	26.70	46.00	-19.30	AVG	P	

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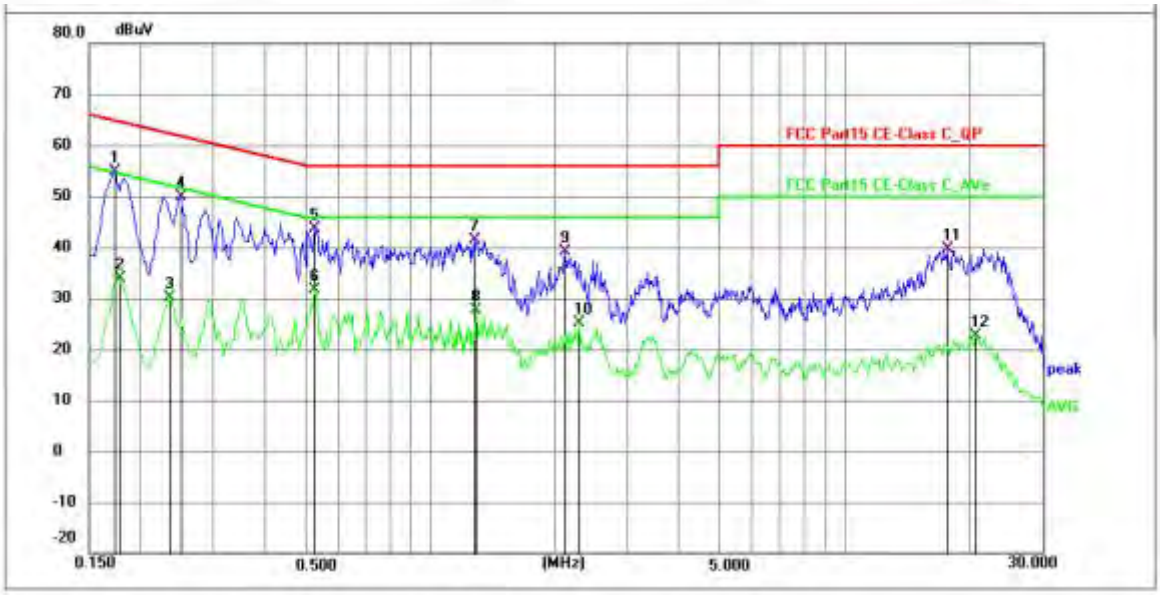
TM1 / Line: Neutral / Band: 2400-2483.5 MHz / BW: 1 / CH: M



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB)	Level (dBuV)	Limit (dBuV)	Margin (dB)	Detector	P/F	Remark
1 *	0.1723	44.28	10.49	54.77	64.85	-10.08	QP	P	
2	0.1770	23.42	10.51	33.93	54.63	-20.70	AVG	P	
3	0.2353	19.48	10.56	30.04	52.26	-22.22	AVG	P	
4	0.2490	39.39	10.56	49.95	61.79	-11.84	QP	P	
5	0.5231	33.09	10.59	43.68	56.00	-12.32	QP	P	
6	0.5231	21.07	10.59	31.66	46.00	-14.34	AVG	P	
7	1.2882	30.74	10.66	41.40	56.00	-14.60	QP	P	
8	1.2930	16.85	10.66	27.51	46.00	-18.49	AVG	P	
9	2.1120	28.33	10.68	39.01	56.00	-16.99	QP	P	
10	2.2964	14.50	10.67	25.17	46.00	-20.83	AVG	P	
11	17.7225	28.78	10.95	39.73	60.00	-20.27	QP	P	
12	20.8094	11.49	11.08	22.57	50.00	-27.43	AVG	P	

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6.2 Occupied Bandwidth

Test Requirement:	47 CFR 15.215(c)
Test Method:	ANSI C63.10-2013, section 7.8.7, For occupied bandwidth measurements, use the procedure in 6.9.2. KDB 558074 D01 15.247 Meas Guidance v05r02
Test Limit:	Refer to 47 CFR 15.215(c), intentional radiators operating under the alternative provisions to the general emission limits, as contained in §§ 15.217 through 15.257 and in subpart E of this part, must be designed to ensure that the 20 dB bandwidth of the emission, or whatever bandwidth may otherwise be specified in the specific rule section under which the equipment operates, is contained within the frequency band designated in the rule section under which the equipment is operated.
Procedure:	a) The spectrum analyzer center frequency is set to the nominal EUT channel center frequency. The span range for the EMI receiver or spectrum analyzer shall be between two times and five times the OBW. b) The nominal IF filter bandwidth (3 dB RBW) shall be in the range of 1% to 5% of the OBW and video bandwidth (VBW) shall be approximately three times RBW, unless otherwise specified by the applicable requirement. c) Set the reference level of the instrument as required, keeping the signal from exceeding the maximum input mixer level for linear operation. In general, the peak of the spectral envelope shall be more than [10 log (OBW/RBW)] below the reference level. Specific guidance is given in 4.1.5.2. d) Steps a) through c) might require iteration to adjust within the specified tolerances. e) The dynamic range of the instrument at the selected RBW shall be more than 10 dB below the target “−xx dB down” requirement; that is, if the requirement calls for measuring the −20 dB OBW, the instrument noise floor at the selected RBW shall be at least 30 dB below the reference value. f) Set detection mode to peak and trace mode to max hold. g) Determine the reference value: Set the EUT to transmit an unmodulated carrier or modulated signal, as applicable. Allow the trace to stabilize. Set the spectrum analyzer marker to the highest level of the displayed trace (this is the reference value). h) Determine the “−xx dB down amplitude” using [(reference value) − xx]. Alternatively, this calculation may be made by using the marker-delta function of the instrument. i) If the reference value is determined by an unmodulated carrier, then turn the EUT modulation ON, and either clear the existing trace or start a new trace on the spectrum analyzer and allow the new trace to stabilize. Otherwise, the trace from step g) shall be used for step j). j) Place two markers, one at the lowest frequency and the other at the highest frequency of the envelope of the spectral display, such that each marker is at or slightly below the “-xx dB down amplitude” determined in step h). If a marker is below this “−xx dB down amplitude” value, then it shall be as close as possible to this value. The occupied bandwidth is the frequency difference between the two markers. Alternatively, set a marker at the lowest frequency of the envelope of the spectral display, such that the marker is at or slightly below the “-xx dB down amplitude” determined in step h). Reset the marker-delta function and move the marker to the other side of the emission until the delta marker amplitude is at the same level as the reference marker amplitude. The marker-delta frequency reading at this point is the specified emission bandwidth. k) The occupied bandwidth shall be reported by providing plot(s) of the measuring instrument display; the plot axes and the scale units per division shall be clearly labeled. Tabular data may be reported in addition to the plot(s).

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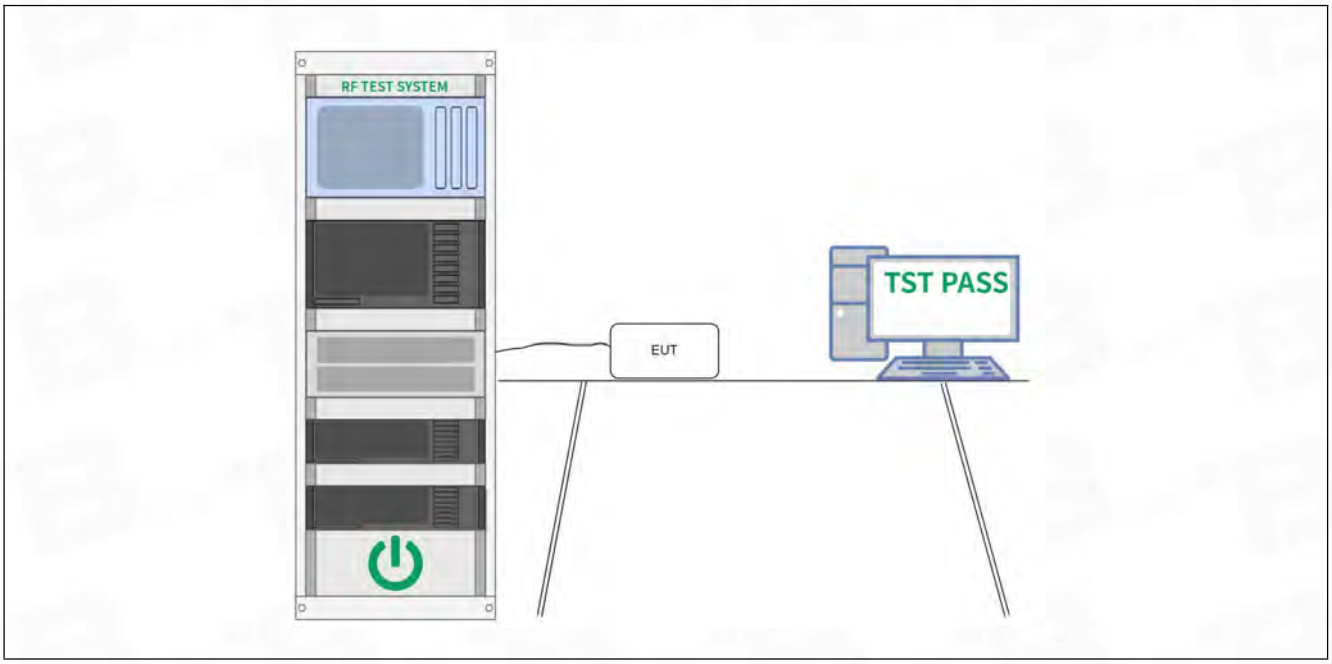
6.2.1 E.U.T. Operation:

Operating Environment:	
Temperature:	22.9 °C
Humidity:	49.6 %
Atmospheric Pressure:	1010 mbar

6.2.2 Test Setup Diagram:



6.2.3 Test Data:

Please Refer to Appendix for Details.

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6.3 Maximum Conducted Output Power

Test Requirement:	47 CFR 15.247(b)(1)
Test Method:	ANSI C63.10-2013, section 7.8.5 KDB 558074 D01 15.247 Meas Guidance v05r02
Test Limit:	Refer to 47 CFR 15.247(b)(1), For frequency hopping systems operating in the 2400-2483.5 MHz band employing at least 75 non-overlapping hopping channels, and all frequency hopping systems in the 5725-5850 MHz band: 1 watt. For all other frequency hopping systems in the 2400-2483.5 MHz band: 0.125 watts.
Procedure:	This is an RF-conducted test to evaluate maximum peak output power. Use a direct connection between the antenna port of the unlicensed wireless device and the spectrum analyzer, through suitable attenuation. The hopping shall be disabled for this test: a) Use the following spectrum analyzer settings: 1) Span: Approximately five times the 20 dB bandwidth, centered on a hopping channel. 2) RBW > 20 dB bandwidth of the emission being measured. 3) VBW >= RBW. 4) Sweep: Auto. 5) Detector function: Peak. 6) Trace: Max hold. b) Allow trace to stabilize. c) Use the marker-to-peak function to set the marker to the peak of the emission. d) The indicated level is the peak output power, after any corrections for external attenuators and cables. e) A plot of the test results and setup description shall be included in the test report. NOTE—A peak responding power meter may be used, where the power meter and sensor system video bandwidth is greater than the occupied bandwidth of the unlicensed wireless device, rather than a spectrum analyzer.

6.3.1 E.U.T. Operation:

Operating Environment:	
Temperature:	22.9 °C
Humidity:	49.6 %
Atmospheric Pressure:	1010 mbar

6.3.2 Test Setup Diagram:

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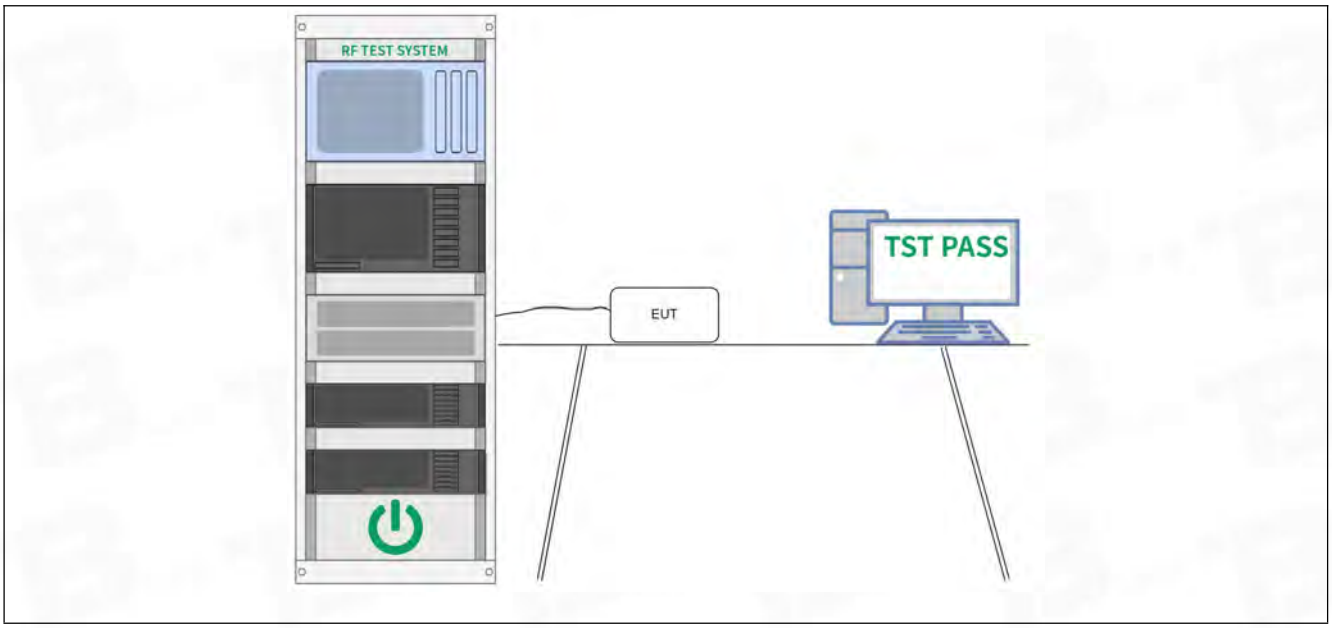

6.3.3 Test Data:

Please Refer to Appendix for Details.

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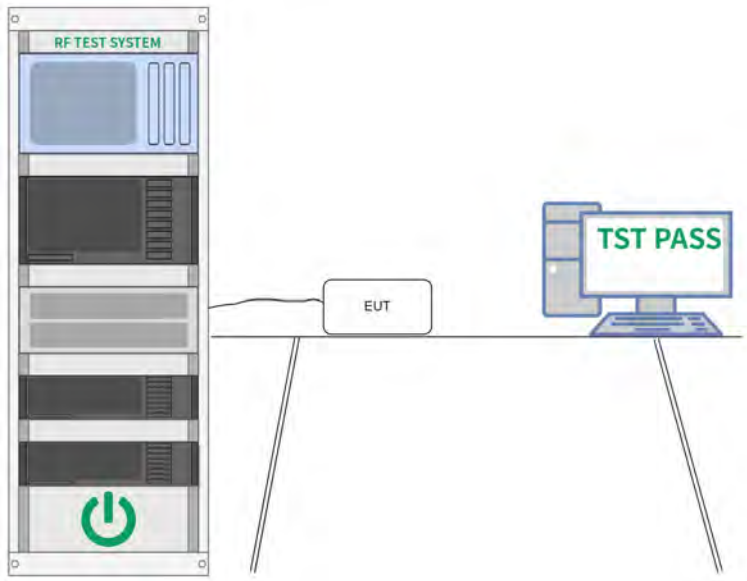
6.4 Channel Separation

Test Requirement:	47 CFR 15.247(a)(1)
Test Method:	ANSI C63.10-2013, section 7.8.2 KDB 558074 D01 15.247 Meas Guidance v05r02
Test Limit:	Refer to 47 CFR 15.247(a)(1), Frequency hopping systems shall have hopping channel carrier frequencies separated by a minimum of 25 kHz or the 20 dB bandwidth of the hopping channel, whichever is greater. Alternatively, frequency hopping systems operating in the 2400-2483.5 MHz band may have hopping channel carrier frequencies that are separated by 25 kHz or two-thirds of the 20 dB bandwidth of the hopping channel, whichever is greater, provided the systems operate with an output power no greater than 125 mW.
Procedure:	The EUT shall have its hopping function enabled. Use the following spectrum analyzer settings: a) Span: Wide enough to capture the peaks of two adjacent channels. b) RBW: Start with the RBW set to approximately 30% of the channel spacing; adjust as necessary to best identify the center of each individual channel. c) Video (or average) bandwidth (VBW) ≥ RBW. d) Sweep: Auto. e) Detector function: Peak. f) Trace: Max hold. g) Allow the trace to stabilize. Use the marker-delta function to determine the separation between the peaks of the adjacent channels. Compliance of an EUT with the appropriate regulatory limit shall be determined. A plot of the data shall be included in the test report.

6.4.1 E.U.T. Operation:

Operating Environment:	
Temperature:	22.9 °C
Humidity:	49.6 %
Atmospheric Pressure:	1010 mbar

6.4.2 Test Setup Diagram:



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6.4.3 Test Data:

Please Refer to Appendix for Details.

6.5 Number of Hopping Frequencies

Test Requirement:	47 CFR 15.247(a)(1)(iii)
Test Method:	ANSI C63.10-2013, section 7.8.3 KDB 558074 D01 15.247 Meas Guidance v05r02
Test Limit:	Refer to 47 CFR 15.247(a)(1)(iii), Fequency hopping systems in the 2400-2483.5 MHz band shall use at least 15 channels. The average time of occupancy on any channel shall not be greater than 0.4 seconds within a period of 0.4 seconds multiplied by the number of hopping channels employed. Frequency hopping systems may avoid or suppress transmissions on a particular hopping frequency provided that a minimum of 15 channels are used.
Procedure:	The EUT shall have its hopping function enabled. Use the following spectrum analyzer settings: a) Span: The frequency band of operation. Depending on the number of channels the device supports, it may be necessary to divide the frequency range of operation across multiple spans, to allow the individual channels to be clearly seen. b) RBW: To identify clearly the individual channels, set the RBW to less than 30% of the channel spacing or the 20 dB bandwidth, whichever is smaller. c) VBW ≥ RBW. d) Sweep: Auto. e) Detector function: Peak. f) Trace: Max hold. g) Allow the trace to stabilize. It might prove necessary to break the span up into subranges to show clearly all of the hopping frequencies. Compliance of an EUT with the appropriate regulatory limit shall be determined for the number of hopping channels. A plot of the data shall be included in the test report.

6.5.1 E.U.T. Operation:

Operating Environment:	
Temperature:	22.9 °C
Humidity:	49.6 %
Atmospheric Pressure:	1010 mbar

6.5.2 Test Setup Diagram:

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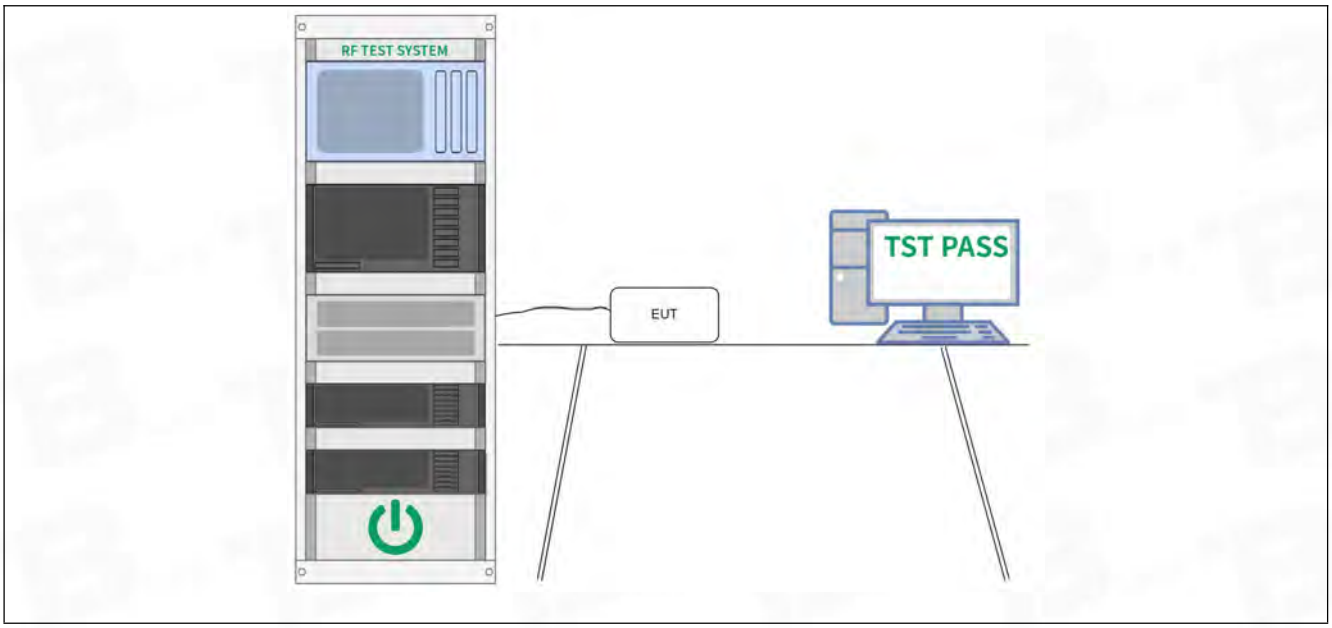

6.5.3 Test Data:

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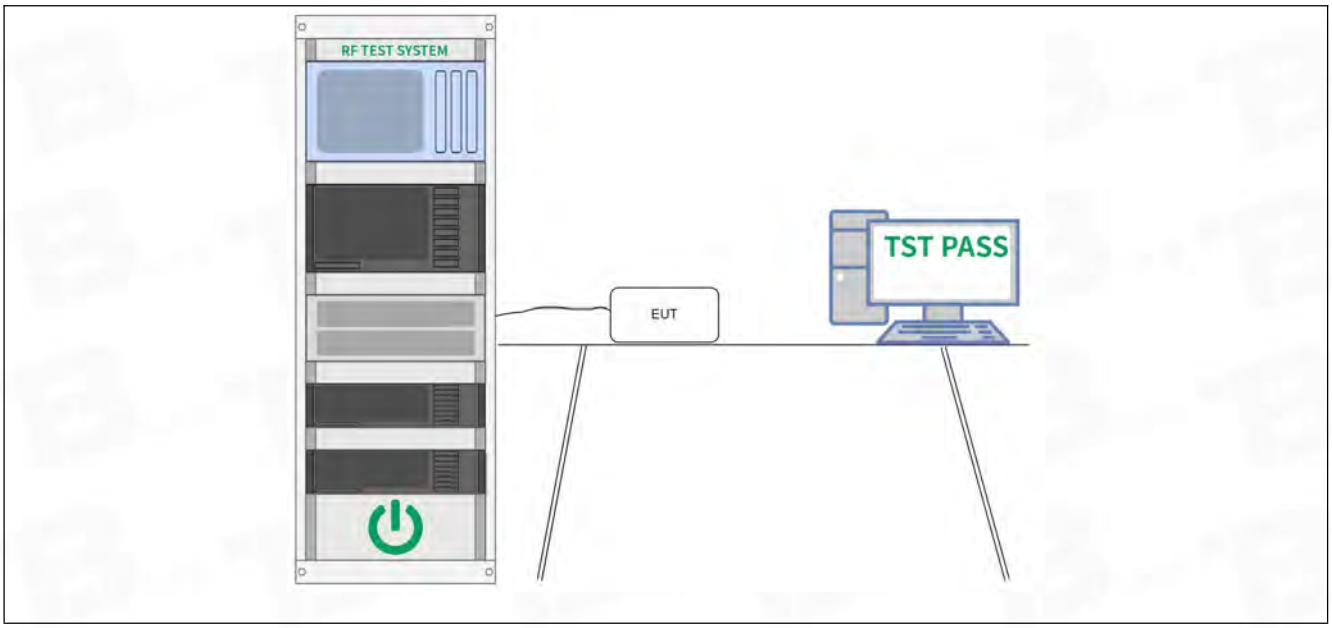
6.6 Dwell Time

Test Requirement:	47 CFR 15.247(a)(1)(iii)
Test Method:	ANSI C63.10-2013, section 7.8.4 KDB 558074 D01 15.247 Meas Guidance v05r02
Test Limit:	Refer to 47 CFR 15.247(a)(1)(iii), Fequency hopping systems in the 2400-2483.5 MHz band shall use at least 15 channels. The average time of occupancy on any channel shall not be greater than 0.4 seconds within a period of 0.4 seconds multiplied by the number of hopping channels employed. Frequency hopping systems may avoid or suppress transmissions on a particular hopping frequency provided that a minimum of 15 channels are used.
Procedure:	The EUT shall have its hopping function enabled. Use the following spectrum analyzer settings: a) Span: Zero span, centered on a hopping channel. b) RBW shall be <= channel spacing and where possible RBW should be set >> 1 / T, where T is the expected dwell time per channel. c) Sweep: As necessary to capture the entire dwell time per hopping channel; where possible use a video trigger and trigger delay so that the transmitted signal starts a little to the right of the start of the plot. The trigger level might need slight adjustment to prevent triggering when the system hops on an adjacent channel; a second plot might be needed with a longer sweep time to show two successive hops on a channel. d) Detector function: Peak. e) Trace: Max hold. Use the marker-delta function to determine the transmit time per hop. If this value varies with different modes of operation (data rate, modulation format, number of hopping channels, etc.), then repeat this test for each variation in transmit time. Repeat the measurement using a longer sweep time to determine the number of hops over the period specified in the requirements. The sweep time shall be equal to, or less than, the period specified in the requirements. Determine the number of hops over the sweep time and calculate the total number of hops in the period specified in the requirements, using the following equation: (Number of hops in the period specified in the requirements) = (number of hops on spectrum analyzer) × (period specified in the requirements / analyzer sweep time) The average time of occupancy is calculated from the transmit time per hop multiplied by the number of hops in the period specified in the requirements. If the number of hops in a specific time varies with different modes of operation (data rate, modulation format, number of hopping channels, etc.), then repeat this test for each variation. The measured transmit time and time between hops shall be consistent with the values described in the operational description for the EUT.

6.6.1 E.U.T. Operation:

Operating Environment:	
Temperature:	22.9 °C
Humidity:	49.6 %
Atmospheric Pressure:	1010 mbar

6.6.2 Test Setup Diagram:



6.6.3 Test Data:

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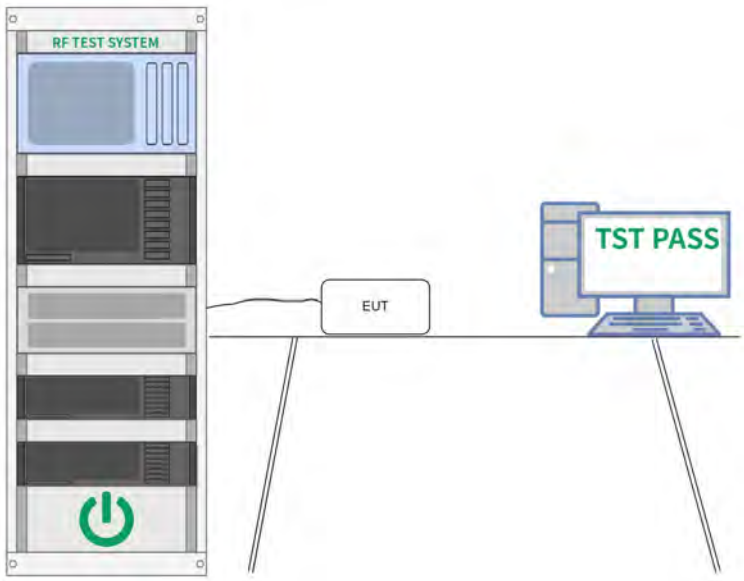
6.7 Emissions in non-restricted frequency bands

Test Requirement:	47 CFR 15.247(d), 15.209, 15.205
Test Method:	ANSI C63.10-2013 section 7.8.8 KDB 558074 D01 15.247 Meas Guidance v05r02
Test Limit:	Refer to 47 CFR 15.247(d), In any 100 kHz bandwidth outside the frequency band in which the spread spectrum or digitally modulated intentional radiator is operating, the radio frequency power that is produced by the intentional radiator shall be at least 20 dB below that in the 100 kHz bandwidth within the band that contains the highest level of the desired power, based on either an RF conducted or a radiated measurement, provided the transmitter demonstrates compliance with the peak conducted power limits. If the transmitter complies with the conducted power limits based on the use of RMS averaging over a time interval, as permitted under paragraph (b)(3) of this section, the attenuation required under this paragraph shall be 30 dB instead of 20 dB. Attenuation below the general limits specified in § 15.209(a) is not required.
Procedure:	Conducted spurious emissions shall be measured for the transmit frequency, per 5.5 and 5.6, and at the maximum transmit powers. Connect the primary antenna port through an attenuator to the spectrum analyzer input; in the results, account for all losses between the unlicensed wireless device output and the spectrum analyzer. The instrument shall span 30 MHz to 10 times the operating frequency in GHz, with a resolution bandwidth of 100 kHz, video bandwidth of 300 kHz, and a coupled sweep time with a peak detector. The band 30 MHz to the highest frequency may be split into smaller spans, as long as the entire spectrum is covered.

6.7.1 E.U.T. Operation:

Operating Environment:	
Temperature:	22.9 °C
Humidity:	49.6 %
Atmospheric Pressure:	1010 mbar

6.7.2 Test Setup Diagram:



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6.7.3 Test Data:

Please Refer to Appendix for Details.

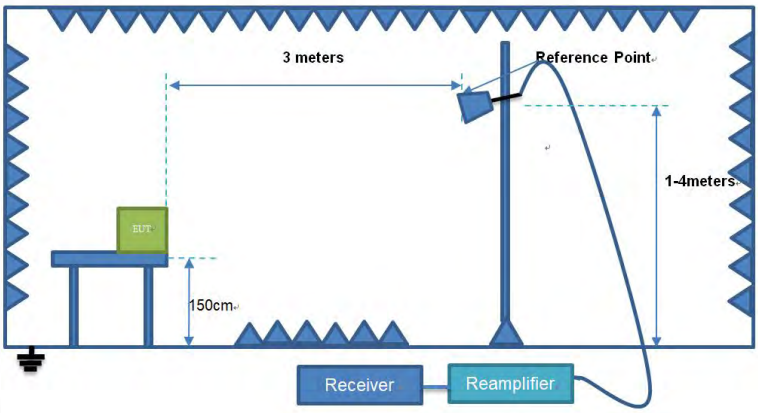
6.8 Band edge emissions (Radiated)

<table>
<tr><td>Test Requirement:</td><td>Refer to 47 CFR 15.247(d), In addition, radiated emissions which fall in the restricted bands, as defined in § 15.205(a), must also comply with the radiated emission limits specified in § 15.209(a)(see § 15.205(c)).`</td></tr>
<tr><td>Test Method:</td><td>ANSI C63.10-2013 section 6.10
KDB 558074 D01 15.247 Meas Guidance v05r02</td></tr>
<tr><td>Test Limit:</td><td>
<table>
<tr><td>Frequency (MHz)</td><td>Field strength (microvolts/meter)</td><td>Measurement distance (meters)</td></tr>
<tr><td>0.009-0.490</td><td>2400/F(kHz)</td><td>300</td></tr>
<tr><td>0.490-1.705</td><td>24000/F(kHz)</td><td>30</td></tr>
<tr><td>1.705-30.0</td><td>30</td><td>30</td></tr>
<tr><td>30-88</td><td>100 **</td><td>3</td></tr>
<tr><td>88-216</td><td>150 **</td><td>3</td></tr>
<tr><td>216-960</td><td>200 **</td><td>3</td></tr>
<tr><td>Above 960</td><td>500</td><td>3</td></tr>
</table>
** Except as provided in paragraph (g), fundamental emissions from intentional radiators operating under this section shall not be located in the frequency bands 54-72 MHz, 76-88 MHz, 174-216 MHz or 470-806 MHz. However, operation within these frequency bands is permitted under other sections of this part, e.g., §§ 15.231 and 15.241.
In the emission table above, the tighter limit applies at the band edges.
The emission limits shown in the above table are based on measurements employing a CISPR quasi-peak detector except for the frequency bands 9–90 kHz, 110–490 kHz and above 1000 MHz. Radiated emission limits in these three bands are based on measurements employing an average detector.
</td></tr>
<tr><td>Procedure:</td><td>ANSI C63.10-2013 section 6.10.5.2</td></tr>
</table>

6.8.1 E.U.T. Operation:

Operating Environment:	
Temperature:	23.1 °C
Humidity:	52.4 %
Atmospheric Pressure:	1010 mbar

6.8.2 Test Setup Diagram:



6.8.3 Test Data:

Note: All the mode have been tested, and only the worst case of mode are in the report

Frequency	Reading Level	Correct Factor	Measurement	Limits	Over	Detector	Polarization
(MHz)	(dBμV)	(dB/m)	(dBμV/m)	(dBμV/m)	(dB)	Peak/AVG	H/V
GFSK – Low band-edge							
(MHz)	(dBμV)	(dB/m)	(dBμV/m)	(dBμV/m)	(dB)	Peak/AVG	H/V
2310	89.11	-49.61	39.50	74	-34.50	Peak	V
2310	79.25	-49.61	29.64	54	-24.36	AVG	V
2390	89.59	-49.5	40.09	74	-33.91	Peak	V
2390	79.48	-49.5	29.98	54	-24.02	AVG	V
2310	89.16	-49.61	39.55	74	-34.45	Peak	H
2310	79.18	-49.61	29.57	54	-24.43	AVG	H
2390	89.11	-49.5	39.61	74	-34.39	Peak	H
2390	79.25	-49.5	29.75	54	-24.25	AVG	H
GFSK – High band-edge							
2483.5	81.25	-49.5	31.75	74	-42.25	Peak	V
2483.5	72.43	-49.5	22.93	54	-31.07	AVG	V
2500	81.52	-49.49	32.03	74	-41.97	Peak	V
2500	72.27	-49.49	22.78	54	-31.22	AVG	V
2483.5	81.42	-49.5	31.92	74	-42.08	Peak	H
2483.5	72.13	-49.5	22.63	54	-31.37	AVG	H
2500	81.54	-49.49	32.05	74	-41.95	Peak	H
2500	72.29	-49.49	22.80	54	-31.20	AVG	H

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6.9 Emissions in frequency bands (below 1GHz)

Test Requirement:	Refer to 47 CFR 15.247(d), In addition, radiated emissions which fall in the restricted bands, as defined in § 15.205(a), must also comply with the radiated emission limits specified in § 15.209(a)(see § 15.205(c)).`
Test Method:	ANSI C63.10-2013 section 6.6.4 KDB 558074 D01 15.247 Meas Guidance v05r02
Test Limit:	

Frequency (MHz)	Field strength (microvolts/meter)	Measurement distance (meters)
0.009-0.490	2400/F(kHz)	300
0.490-1.705	24000/F(kHz)	30
1.705-30.0	30	30
30-88	100 **	3
88-216	150 **	3
216-960	200 **	3
Above 960	500	3

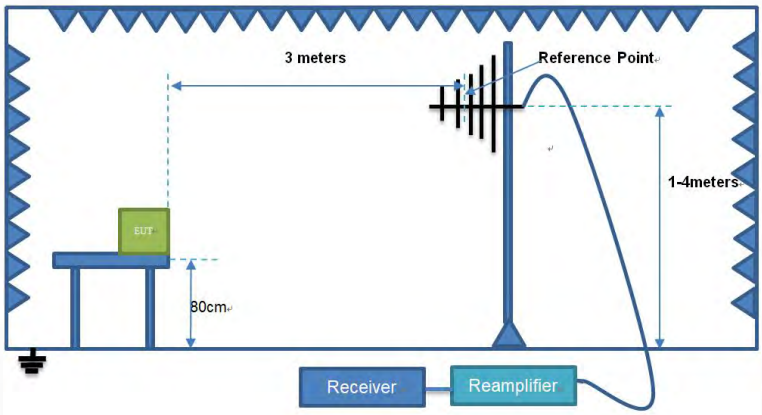
** Except as provided in paragraph (g), fundamental emissions from intentional radiators operating under this section shall not be located in the frequency bands 54-72 MHz, 76-88 MHz, 174-216 MHz or 470-806 MHz. However, operation within these frequency bands is permitted under other sections of this part, e.g., §§ 15.231 and 15.241.
In the emission table above, the tighter limit applies at the band edges.
The emission limits shown in the above table are based on measurements employing a CISPR quasi-peak detector except for the frequency bands 9–90 kHz, 110–490 kHz and above 1000 MHz. Radiated emission limits in these three bands are based on measurements employing an average detector.

Procedure:	ANSI C63.10-2013 section 6.6.4

6.9.1 E.U.T. Operation:

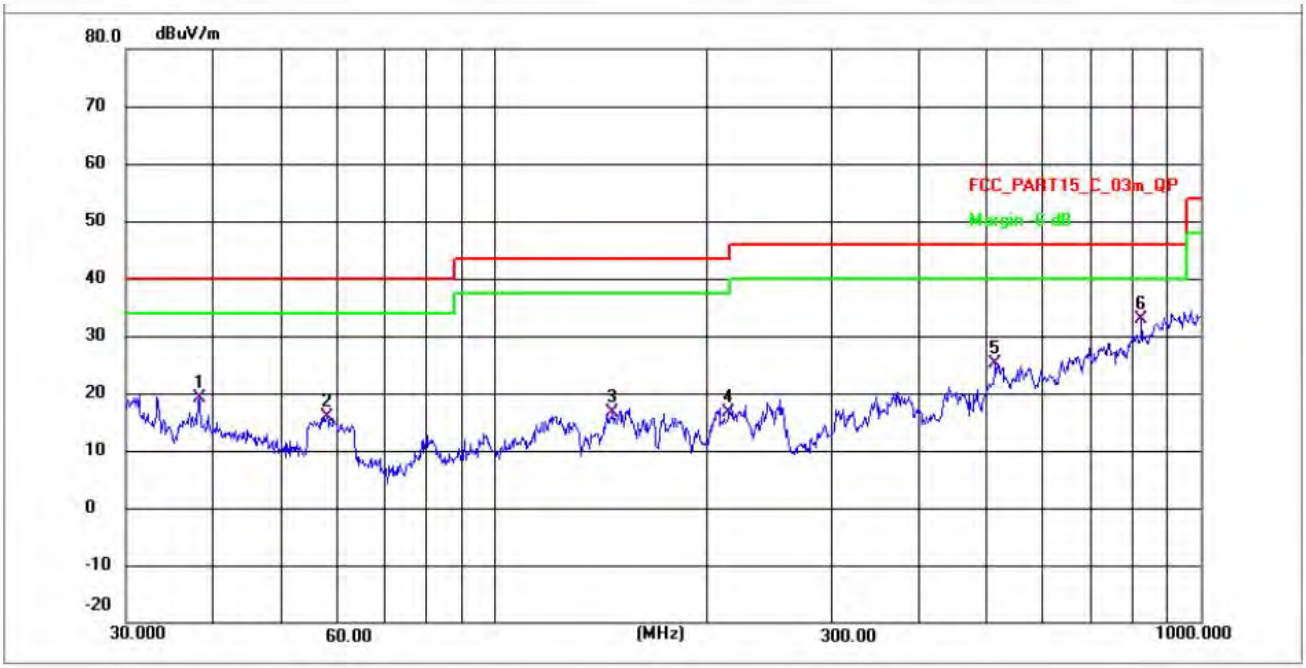
Operating Environment:	
Temperature:	24.6 °C
Humidity:	52 %
Atmospheric Pressure:	1010 mbar

6.9.2 Test Setup Diagram:



6.9.3 Test Data:

TM1 / Polarization: Horizontal / Band: 2400-2483.5 MHz / BW: 1 / CH: M



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	P/F
1	38.1450	28.87	-9.64	19.23	40.00	-20.77	QP	P
2	57.8975	25.24	-9.47	15.77	40.00	-24.23	QP	P
3	147.4036	38.56	-22.03	16.53	43.50	-26.97	QP	P
4	215.2675	37.92	-21.38	16.54	43.50	-26.96	QP	P
5	512.7332	44.08	-18.90	25.18	46.00	-20.82	QP	P
6 *	827.4932	50.32	-17.41	32.91	46.00	-13.09	QP	P

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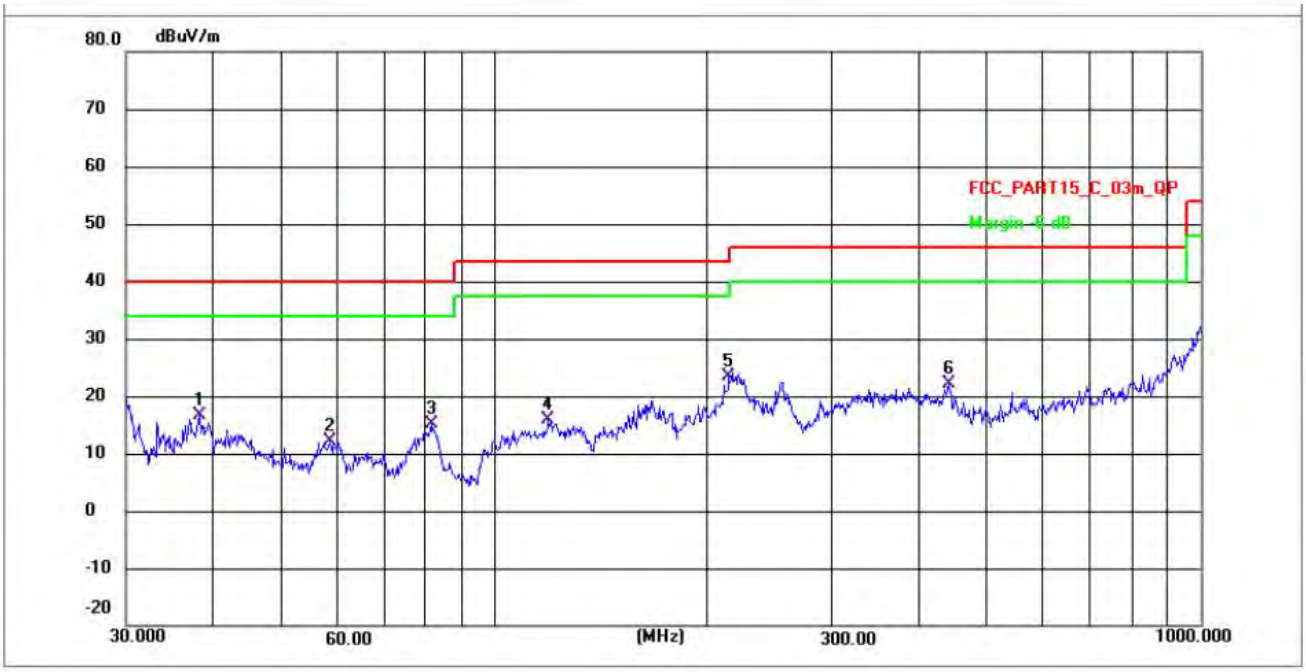
TM1 / Polarization: Vertical / Band: 2400-2483.5 MHz / BW: 1 / CH: M



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	P/F
1	38.2120	26.33	-9.64	16.69	40.00	-23.31	QP	P
2	58.5100	21.53	-9.47	12.06	40.00	-27.94	QP	P
3	81.2116	24.33	-9.27	15.06	40.00	-24.94	QP	P
4	119.2266	38.11	-22.30	15.81	43.50	-27.69	QP	P
5 *	214.8907	44.75	-21.39	23.36	43.50	-20.14	QP	P
6	441.7425	41.68	-19.48	22.20	46.00	-23.80	QP	P

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6.10 Emissions in frequency bands (above 1GHz)

Test Requirement:	In addition, radiated emissions which fall in the restricted bands, as defined in § 15.205(a), must also comply with the radiated emission limits specified in § 15.209(a)(see § 15.205(c)).`
Test Method:	ANSI C63.10-2013 section 6.6.4 KDB 558074 D01 15.247 Meas Guidance v05r02
Test Limit:	

Frequency (MHz)	Field strength (microvolts/meter)	Measurement distance (meters)
0.009-0.490	2400/F(kHz)	300
0.490-1.705	24000/F(kHz)	30
1.705-30.0	30	30
30-88	100 **	3
88-216	150 **	3
216-960	200 **	3
Above 960	500	3

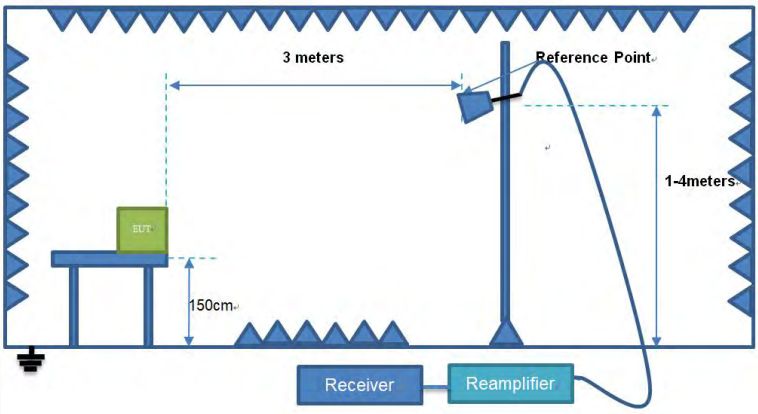
** Except as provided in paragraph (g), fundamental emissions from intentional radiators operating under this section shall not be located in the frequency bands 54-72 MHz, 76-88 MHz, 174-216 MHz or 470-806 MHz. However, operation within these frequency bands is permitted under other sections of this part, e.g., §§ 15.231 and 15.241.
In the emission table above, the tighter limit applies at the band edges.
The emission limits shown in the above table are based on measurements employing a CISPR quasi-peak detector except for the frequency bands 9–90 kHz, 110–490 kHz and above 1000 MHz. Radiated emission limits in these three bands are based on measurements employing an average detector.

Procedure:	ANSI C63.10-2013 section 6.6.4

6.10.1 E.U.T. Operation:

Operating Environment:	
Temperature:	24.4 °C
Humidity:	54 %
Atmospheric Pressure:	1010 mbar

6.10.2 Test Setup Diagram:



6.10.3 Test Data:

Note: All the mode have been tested, and only the worst case of mode are in the report

Frequency	Reading Level	Correct Factor	Measurement	Limits	Over	Detector	Polarization
(MHz)	(dBμV)	(dB/m)	(dBμV/m)	(dBμV/m)	(dB)	Peak/AVG	H/V
GFSK - 2402 MHz TX mode							
4804	88.80	-48.88	39.92	74.00	-34.08	Peak	V
4804	74.39	-48.88	25.51	54.00	-28.49	AVG	V
7206	88.52	-47.21	41.31	74.00	-32.69	Peak	V
7206	74.56	-47.21	27.35	54.00	-26.65	AVG	V
9608	88.55	-45.57	42.98	74.00	-31.02	Peak	V
9608	74.25	-45.57	28.68	54.00	-25.32	AVG	V
4804	88.77	-48.88	39.89	74.00	-34.11	Peak	H
4804	74.59	-48.88	25.71	54.00	-28.29	AVG	H
7206	88.57	-47.21	41.36	74.00	-32.64	Peak	H
7206	74.29	-47.21	27.08	54.00	-26.92	AVG	H
9608	88.85	-45.57	43.28	74.00	-30.72	Peak	H
9608	74.33	-45.57	28.76	54.00	-25.24	AVG	H
GFSK - 2441 MHz TX mode							
4882	87.42	-48.83	38.59	74.00	-35.41	Peak	V
4882	76.36	-48.83	27.53	54.00	-26.47	AVG	V
7323	87.53	-46.88	40.65	74.00	-33.35	Peak	V
7323	76.31	-46.88	29.43	54.00	-24.57	AVG	V
9764	87.31	-45.52	41.79	74.00	-32.21	Peak	V
9764	76.08	-45.52	30.56	54.00	-23.44	AVG	V
4882	87.62	-48.83	38.79	74.00	-35.21	Peak	H
4882	76.19	-48.83	27.36	54.00	-26.64	AVG	H
7323	87.62	-46.88	40.74	74.00	-33.26	Peak	H
7323	75.98	-46.88	29.10	54.00	-24.90	AVG	H
9764	87.60	-45.52	42.08	74.00	-31.92	Peak	H
9764	76.38	-45.52	30.86	54.00	-23.14	AVG	H
GFSK - 2480 MHz TX mode							
4960	89.70	-48.78	40.92	74.00	-33.08	Peak	V
4960	75.53	-48.78	26.75	54.00	-27.25	AVG	V
7440	89.83	-46.75	43.08	74.00	-30.92	Peak	V
7440	75.54	-46.75	28.79	54.00	-25.21	AVG	V
9920	89.67	-45.45	44.22	74.00	-29.78	Peak	V
9920	75.79	-45.45	30.34	54.00	-23.66	AVG	V
4960	89.66	-48.78	40.88	74.00	-33.12	Peak	H
4960	75.60	-48.78	26.82	54.00	-27.18	AVG	H
7440	89.44	-46.75	42.69	74.00	-31.31	Peak	H
7440	75.39	-46.75	28.64	54.00	-25.36	AVG	H

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9920	89.55	-45.45	44.10	74.00	-29.90	Peak	H
9920	75.60	-45.45	30.15	54.00	-23.85	AVG	H

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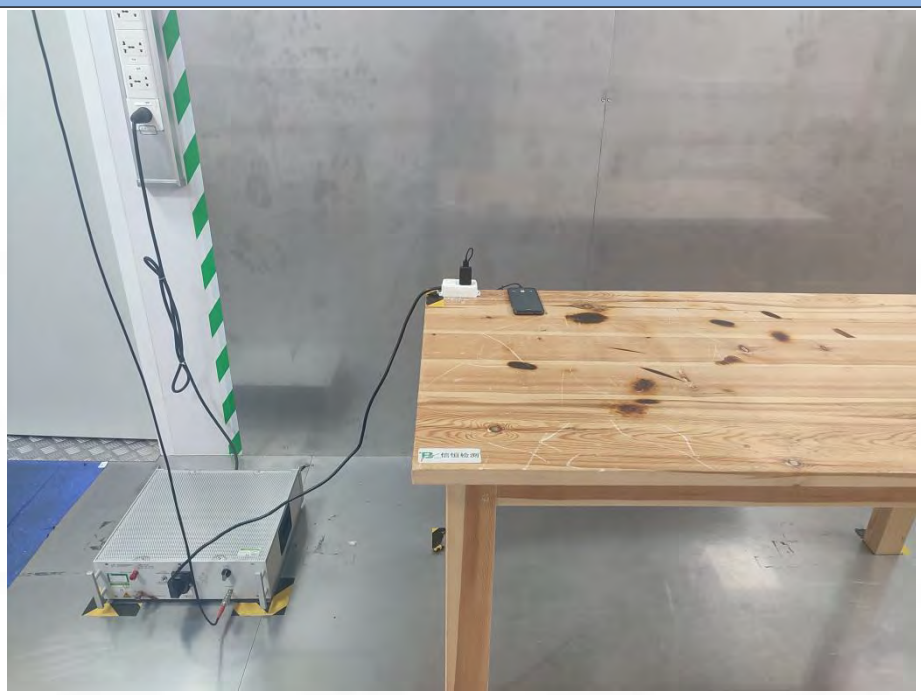
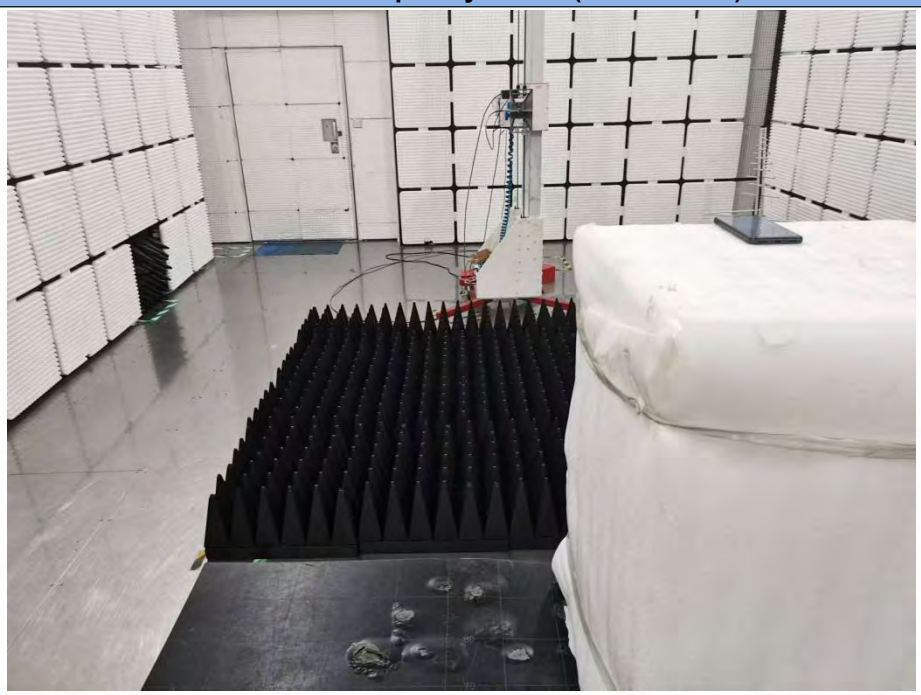
7 Test Setup Photos

Conducted Emission at AC power line


Band edge emissions (Radiated) Emissions in frequency bands (above 1GHz)


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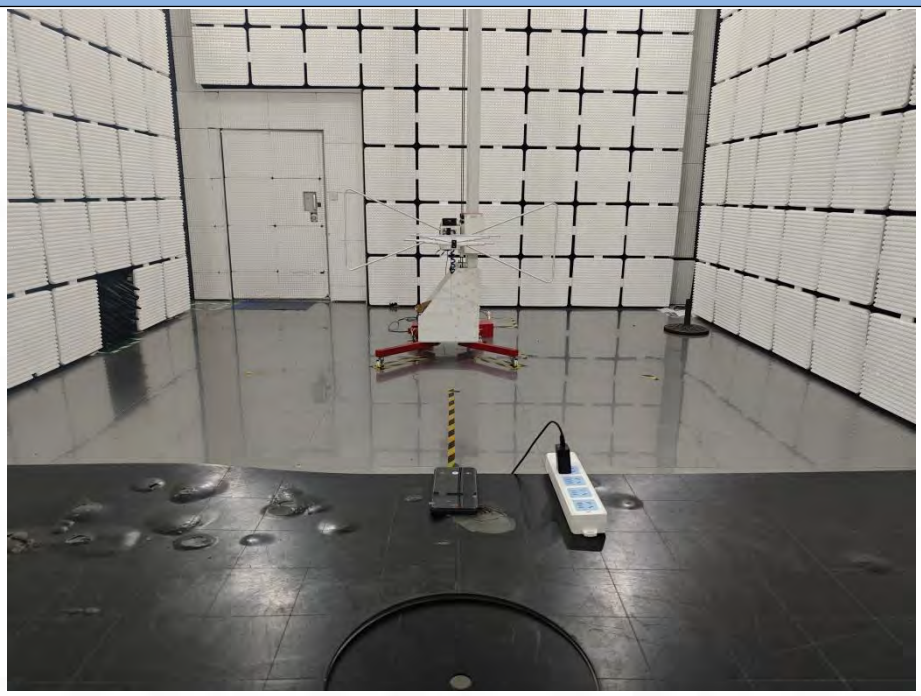
Emissions in frequency bands (below 1GHz)


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Appendix

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1. Bandwidth

1.1 Test Result

1.1.1 OBW

Mode	TX Type	Frequency (MHz)	Packet Type	ANT	99% Occupied Bandwidth (MHz)		Verdict
					Result	Limit	
GFSK	SISO	2402	DH5	1	0.856	/	Pass
		2441	DH5	1	0.854	/	Pass
		2480	DH5	1	0.854	/	Pass
Pi/4DQPSK	SISO	2402	2DH5	1	1.182	/	Pass
		2441	2DH5	1	1.183	/	Pass
		2480	2DH5	1	1.183	/	Pass
8DPSK	SISO	2402	3DH5	1	1.185	/	Pass
		2441	3DH5	1	1.184	/	Pass
		2480	3DH5	1	1.185	/	Pass

1.1.2 20dB BW

Mode	TX Type	Frequency (MHz)	Packet Type	ANT	20dB Bandwidth (MHz)		Verdict
					Result	Limit	
GFSK	SISO	2402	DH5	1	0.944	/	Pass
		2441	DH5	1	0.942	/	Pass
		2480	DH5	1	0.943	/	Pass
Pi/4DQPSK	SISO	2402	2DH5	1	1.288	/	Pass
		2441	2DH5	1	1.289	/	Pass
		2480	2DH5	1	1.289	/	Pass
8DPSK	SISO	2402	3DH5	1	1.297	/	Pass
		2441	3DH5	1	1.295	/	Pass
		2480	3DH5	1	1.297	/	Pass

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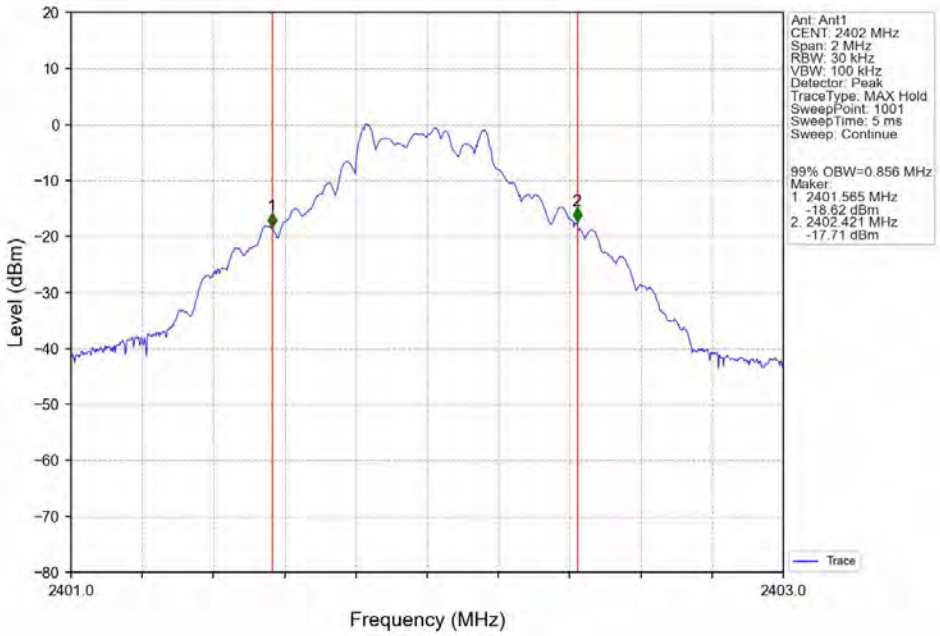
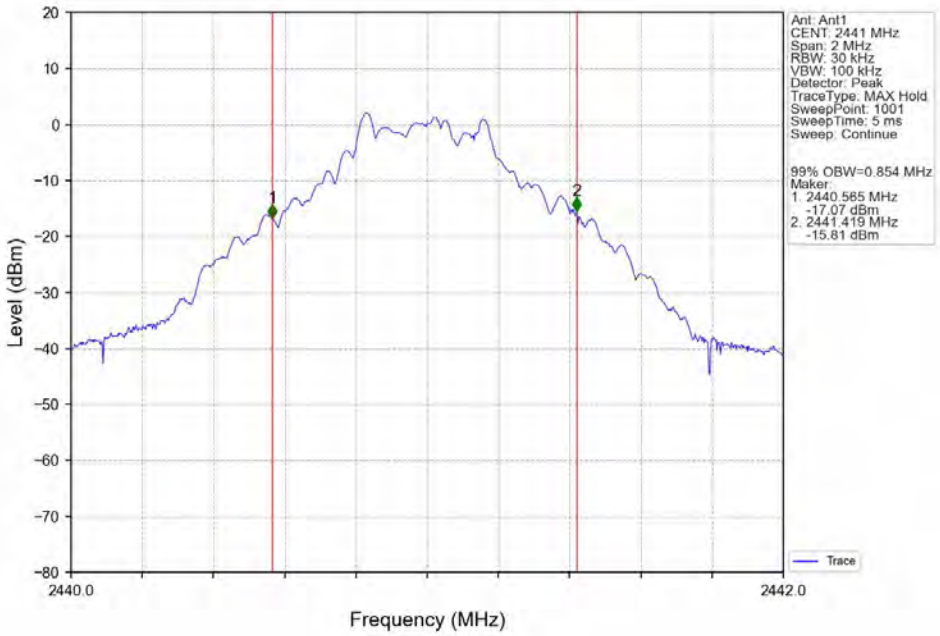
1.2 Test Graph

1.2.1 OBW

GFSK_DH5_LCH_2402MHz_Ant1_NTNV



GFSK_DH5_MCH_2441MHz_Ant1_NTNV



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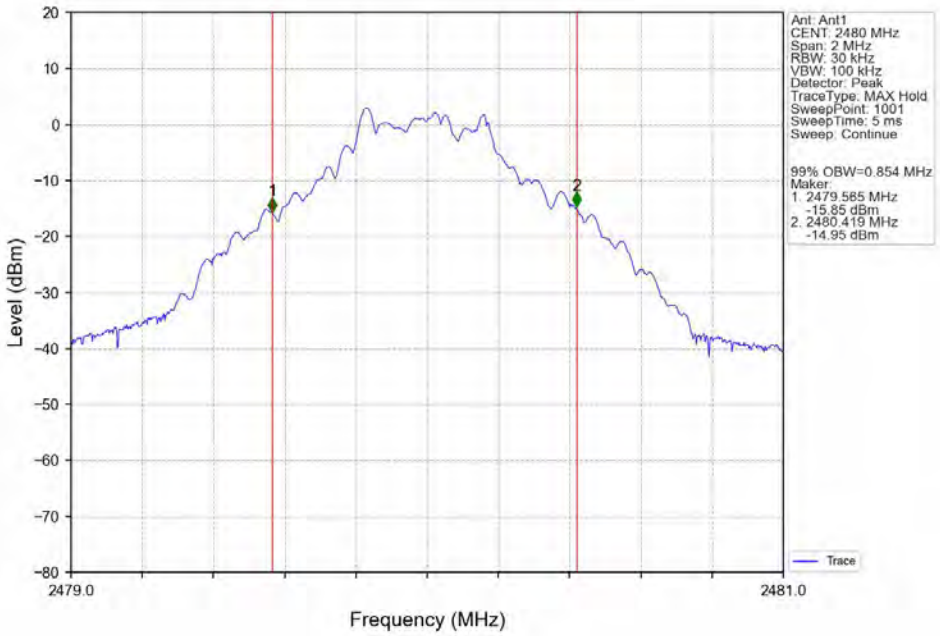
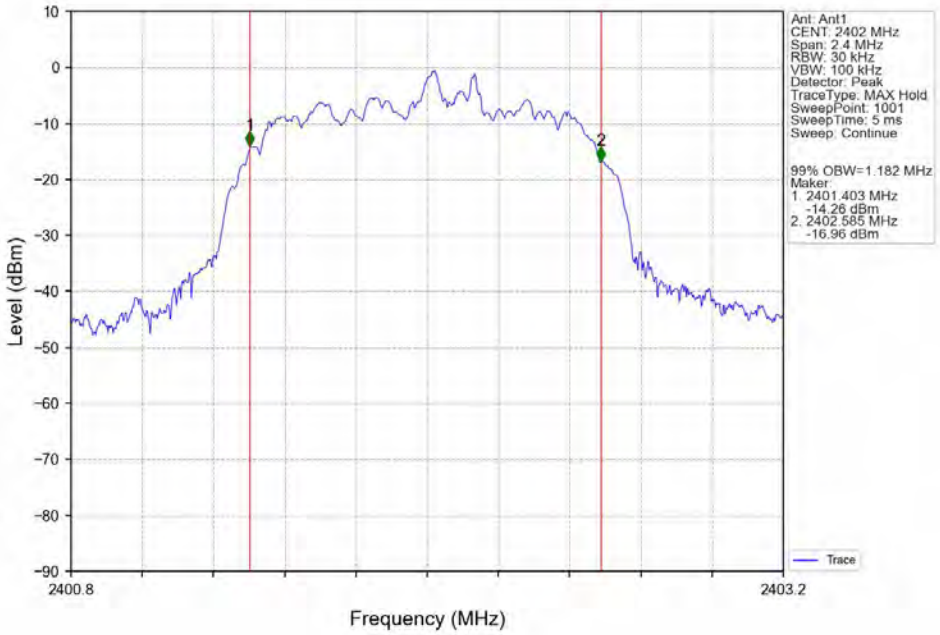
GFSK_DH5_HCH_2480MHz_Ant1_NTNV



Pi/4DQPSK_2DH5_LCH_2402MHz_Ant1_NTNV



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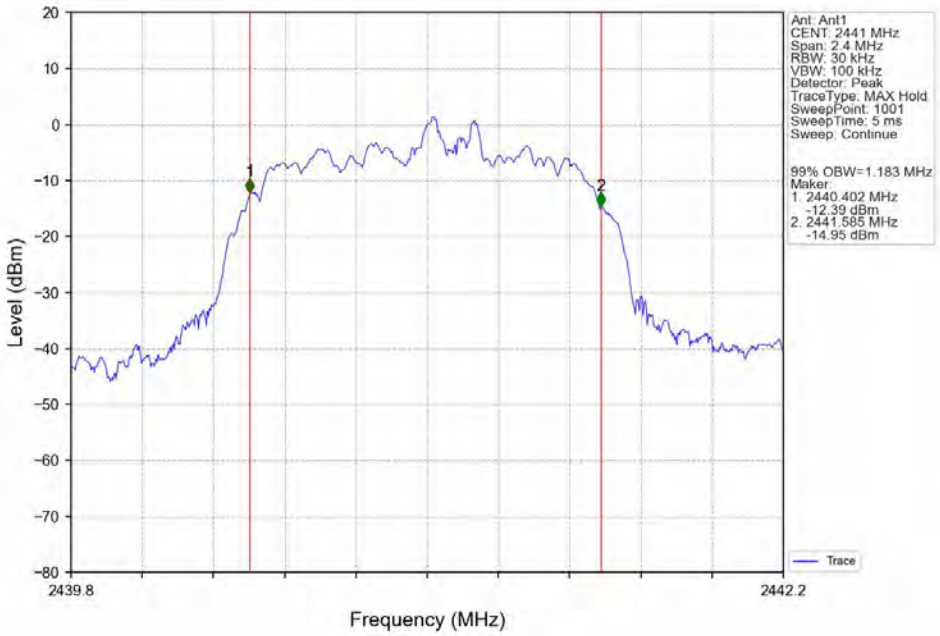
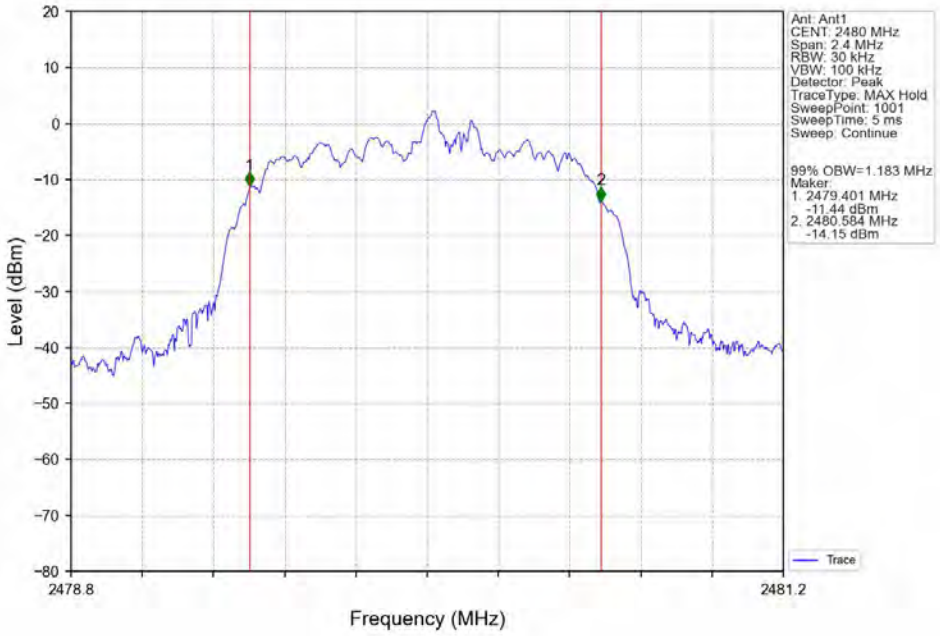
Pi/4DQPSK_2DH5_MCH_2441MHz_Ant1_NTNV



Pi/4DQPSK_2DH5_HCH_2480MHz_Ant1_NTNV



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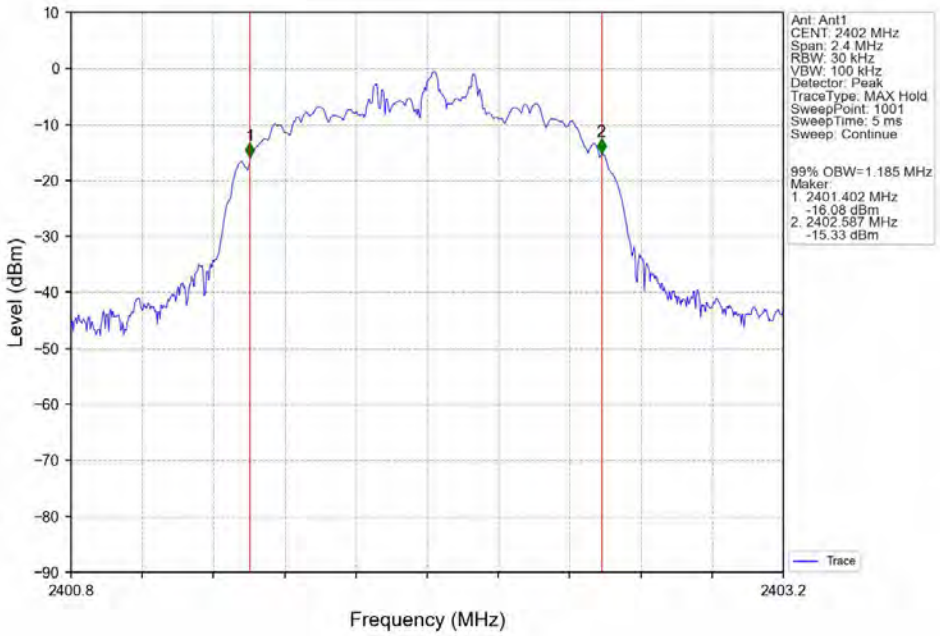
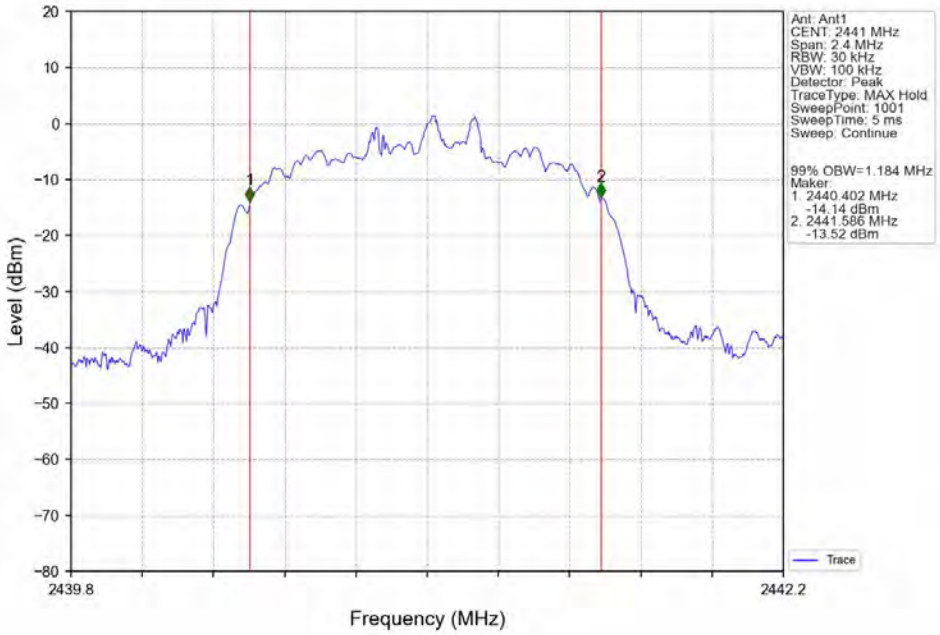
8DPSK_3DH5_LCH_2402MHz_Ant1_NTNV



8DPSK_3DH5_MCH_2441MHz_Ant1_NTNV



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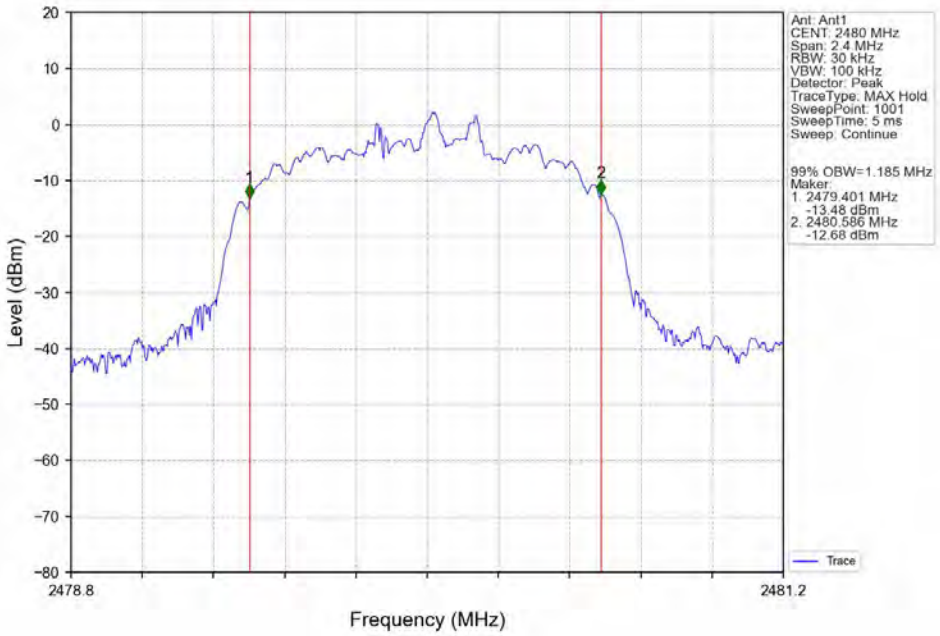
8DPSK_3DH5_HCH_2480MHz_Ant1_NTNV



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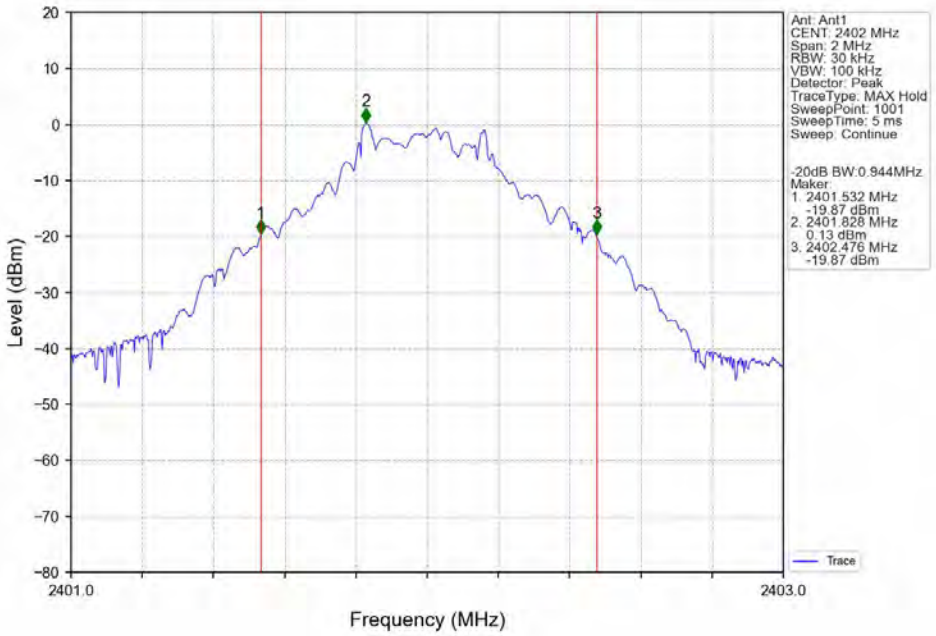
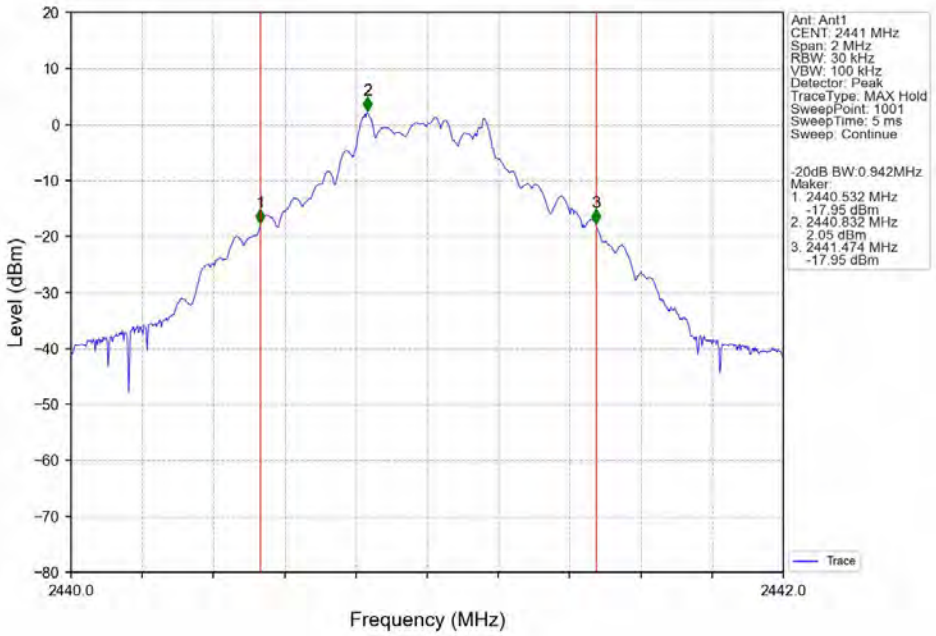
1.2.2 20dB BW

GFSK_DH5_LCH_2402MHz_Ant1_NTNV



GFSK_DH5_MCH_2441MHz_Ant1_NTNV



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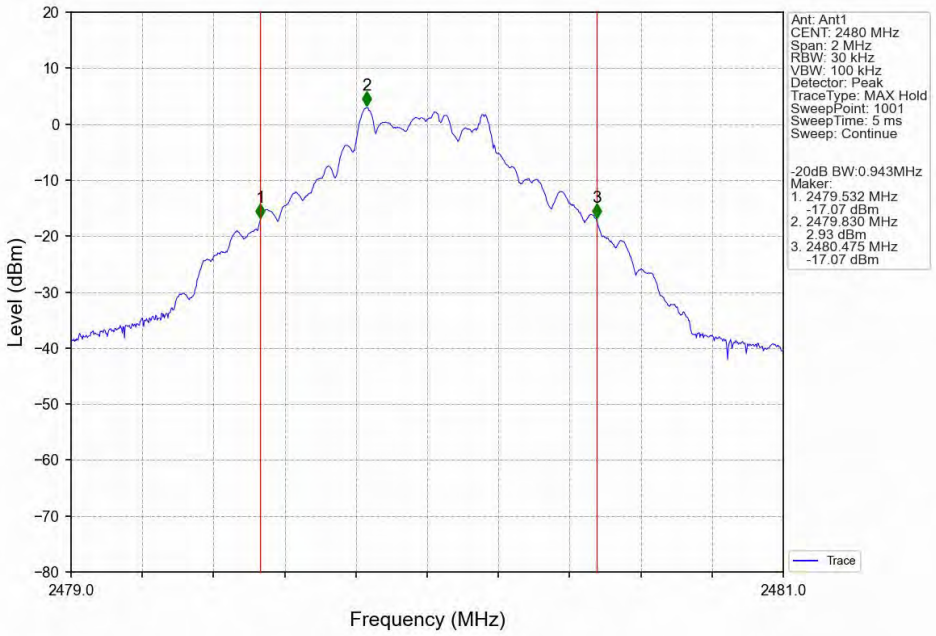
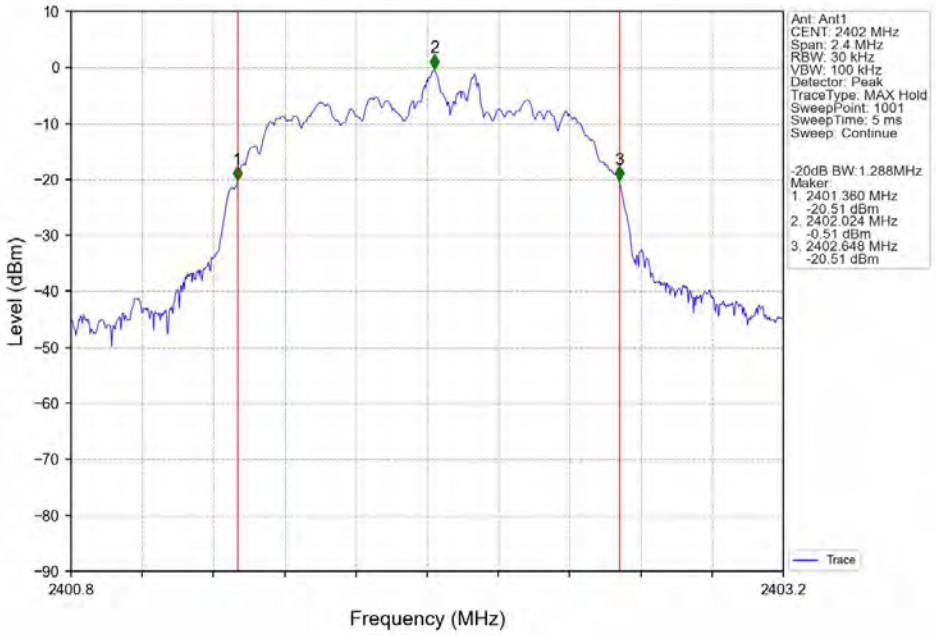
GFSK_DH5_HCH_2480MHz_Ant1_NTNV



Pi/4DQPSK_2DH5_LCH_2402MHz_Ant1_NTNV



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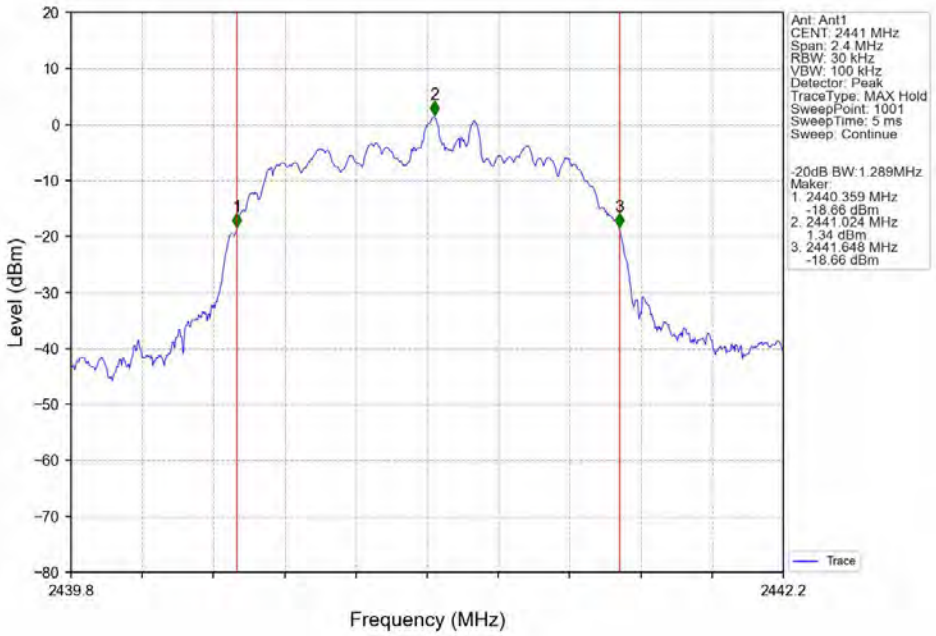
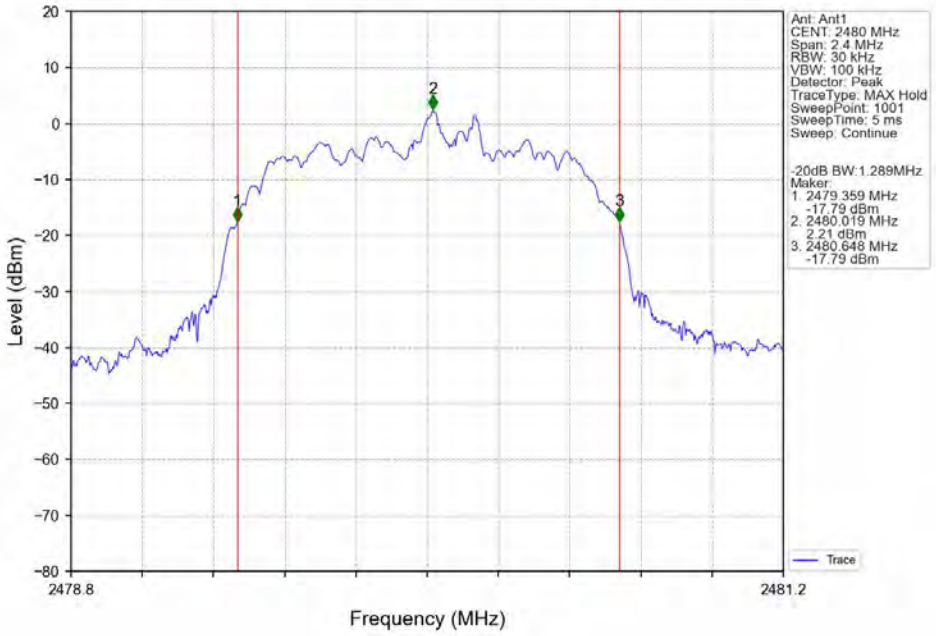
Pi/4DQPSK_2DH5_MCH_2441MHz_Ant1_NTNV



Pi/4DQPSK_2DH5_HCH_2480MHz_Ant1_NTNV



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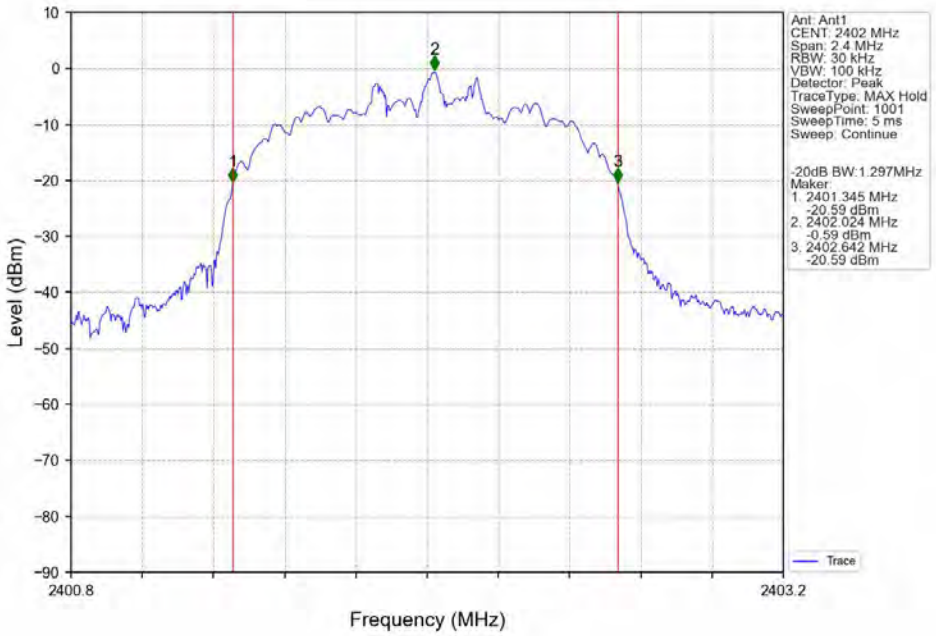
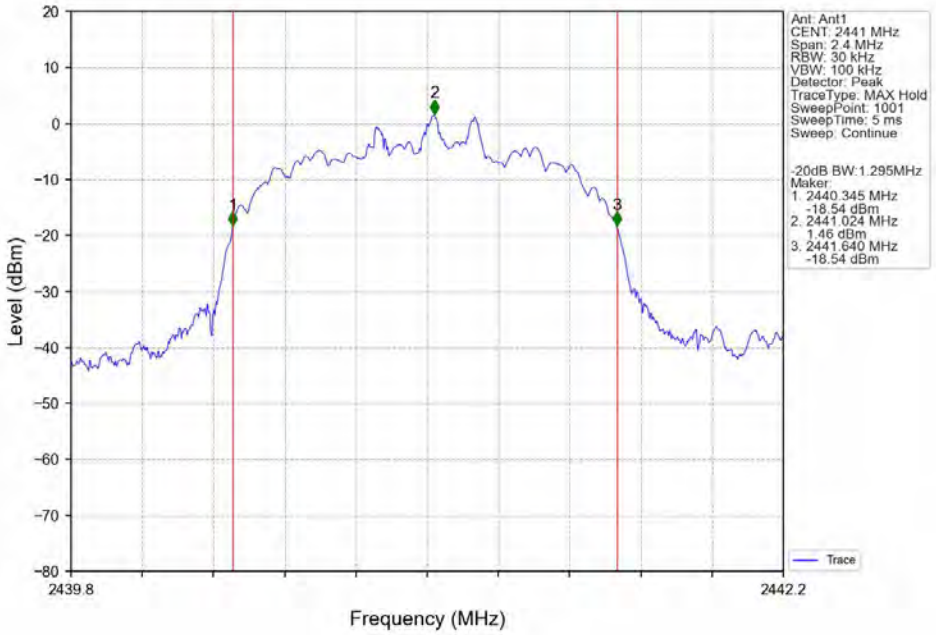
8DPSK_3DH5_LCH_2402MHz_Ant1_NTNV



8DPSK_3DH5_MCH_2441MHz_Ant1_NTNV



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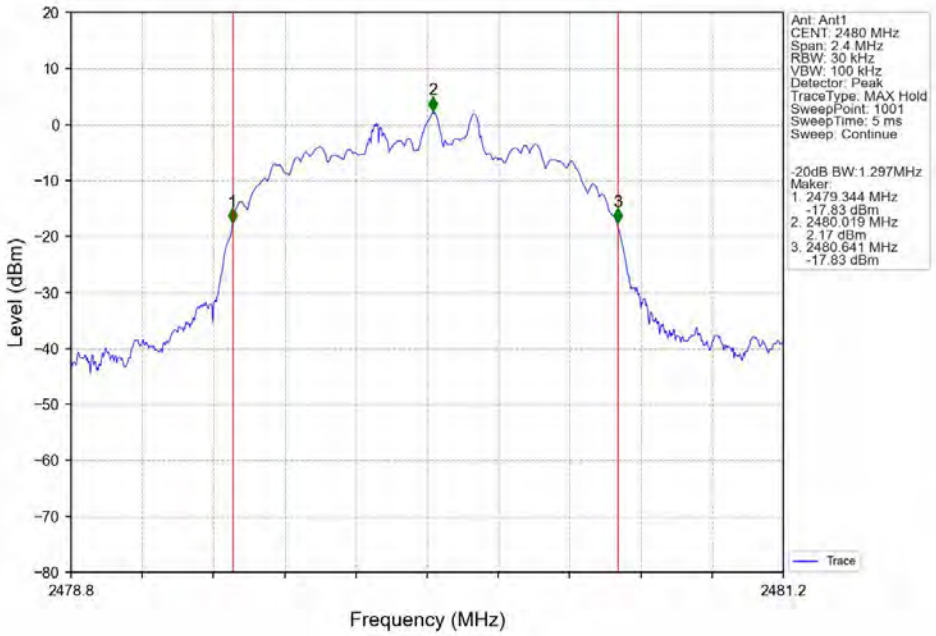
8DPSK_3DH5_HCH_2480MHz_Ant1_NTNV



2. Maximum Conducted Output Power

2.1 Test Result

2.1.1 Power

Mode	TX Type	Frequency (MHz)	Packet Type	Maximum Peak Conducted Output Power (dBm)		Verdict
				ANT1	Limit	
GFSK	SISO	2402	DH5	1.27	<=30	Pass
		2441	DH5	3.24	<=30	Pass
		2480	DH5	4.06	<=30	Pass
Pi/4DQPSK	SISO	2402	2DH5	3.33	<=20.97	Pass
		2441	2DH5	5.19	<=20.97	Pass
		2480	2DH5	6.04	<=20.97	Pass
8DPSK	SISO	2402	3DH5	3.76	<=20.97	Pass
		2441	3DH5	5.66	<=20.97	Pass
		2480	3DH5	6.45	<=20.97	Pass
Note1: Antenna Gain: Ant1: 0.65dBi;						

3. Carrier Frequency Separation

3.1 Test Result

3.1.1 Ant1

Ant1							
Mode	TX Type	Frequency (MHz)	Packet Type	Channel Separation (MHz)	20dB Bandwidth (MHz)	Limit (MHz)	Verdict
GFSK	SISO	HOPP	DH5	0.990	0.944	>=0.944	Pass
Pi/4DQPSK	SISO	HOPP	2DH5	1.010	1.289	>=0.859	Pass
8DPSK	SISO	HOPP	3DH5	1.013	1.297	>=0.865	Pass

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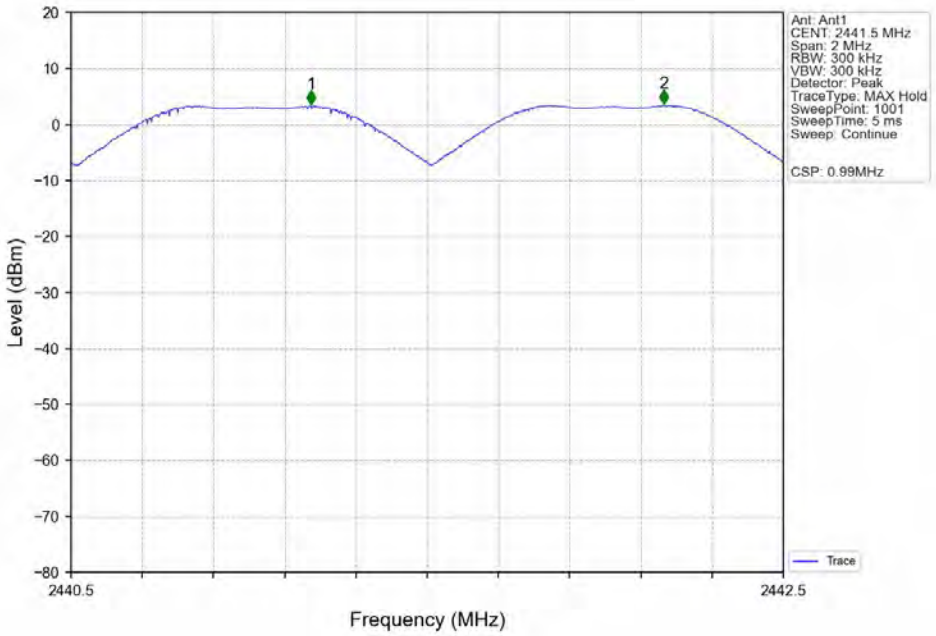
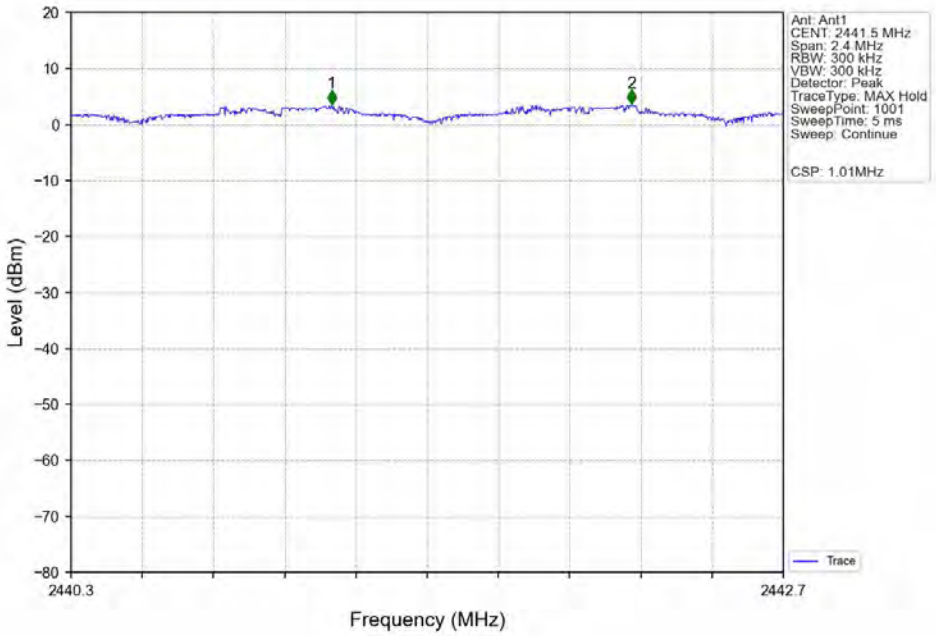
3.2 Test Graph

3.2.1 Ant1

GFSK_DH5_HOPP_Ant1_NTNV



Pi/4DQPSK_2DH5_HOPP_Ant1_NTNV



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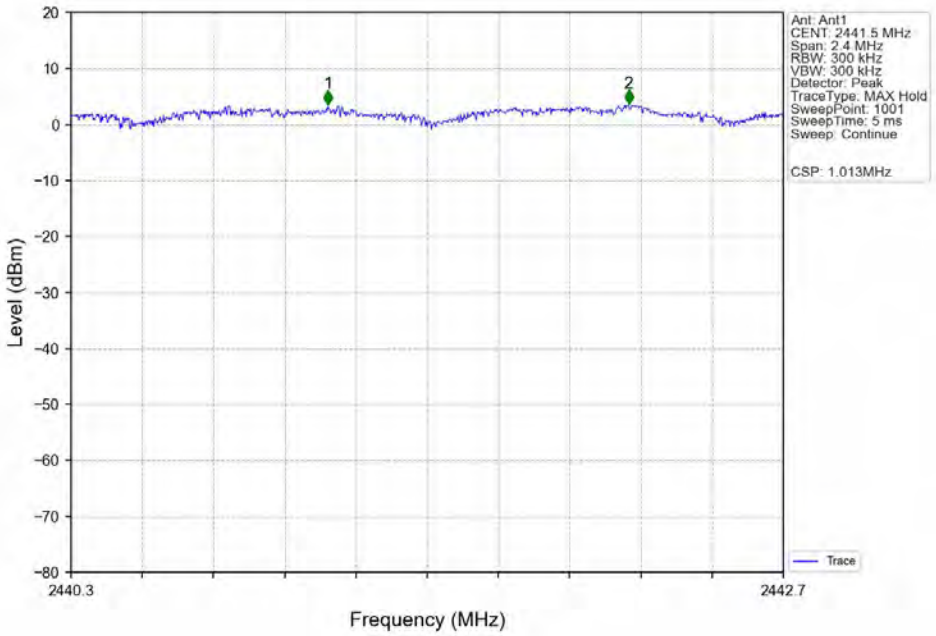
8DPSK_3DH5_HOPP_Ant1_NTNV



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4. Number of Hopping Frequencies

4.1 Test Result

4.1.1 HoppNum

Mode	TX Type	Frequency (MHz)	Packet Type	Num of Hopping Frequencies		Verdict
				ANT1	Limit	
GFSK	SISO	HOPP	DH5	79	>=15	Pass
Pi/4DQPSK	SISO	HOPP	2DH5	79	>=15	Pass
8DPSK	SISO	HOPP	3DH5	79	>=15	Pass

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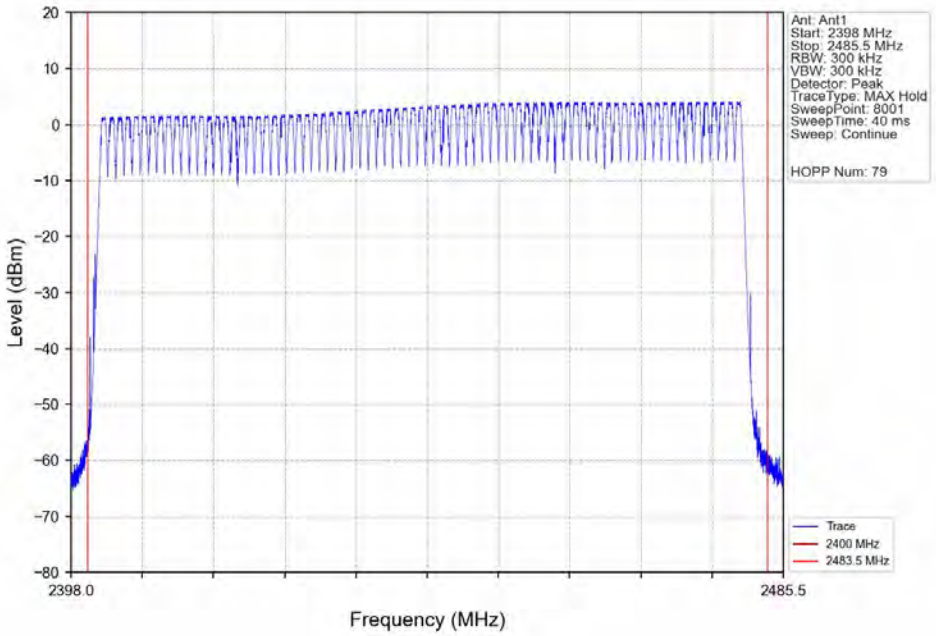
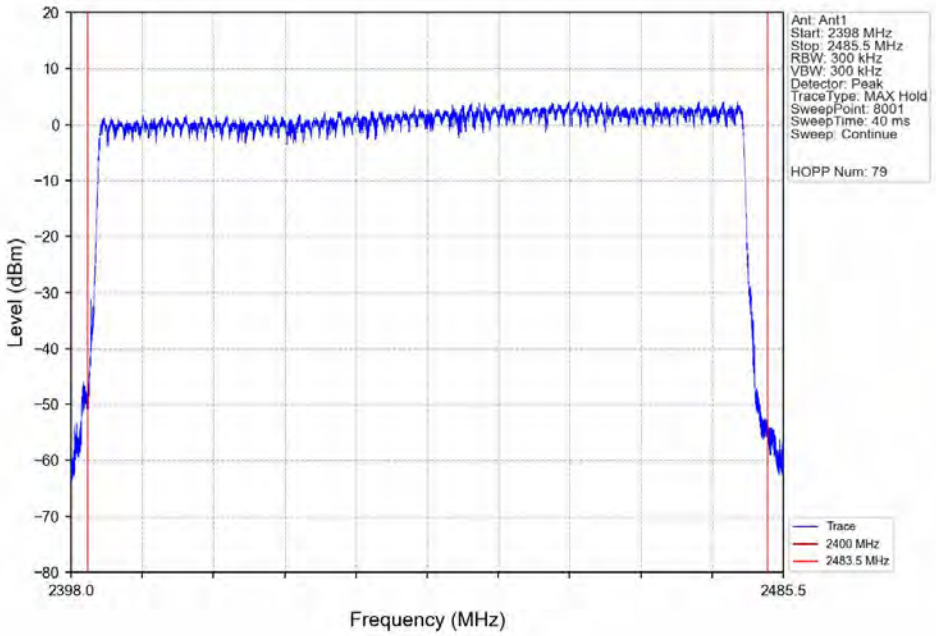
4.2 Test Graph

4.2.1 HoppNum

GFSK_DH5_HOPP_Ant1_NTNV



Pi/4DQPSK_2DH5_HOPP_Ant1_NTNV



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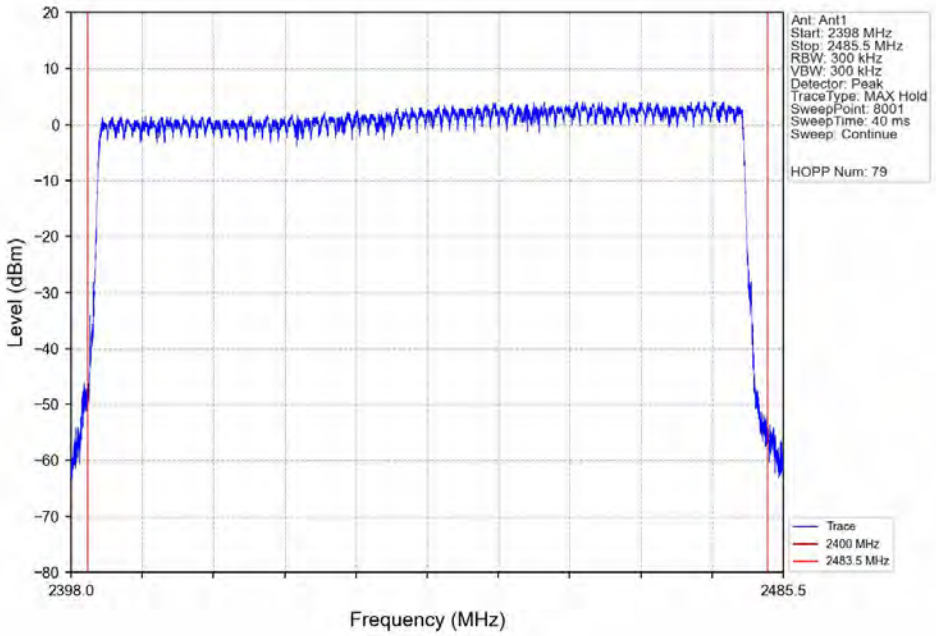
8DPSK_3DH5_HOPP_Ant1_NTNV



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5. Time of Occupancy (Dwell Time)

5.1 Test Result

5.1.1 Ant1

Ant1									
Mode	TX Type	Frequency (MHz)	Packet Type	Duration of Single Pulse (ms)	Observation Period (s)	Num of Pulse in Observation Period	Dwell Time (ms)	Limit (ms)	Verdict
GFSK	SISO	HOPP	DH1	0.410	31.600	318	130.380	<=400	Pass
			DH3	1.668	31.600	150	250.200	<=400	Pass
			DH5	2.900	31.600	97	281.300	<=400	Pass
Pi/4DQPSK	SISO	HOPP	2DH1	0.388	31.600	317	122.996	<=400	Pass
			2DH3	1.653	31.600	163	269.439	<=400	Pass
			2DH5	2.888	31.600	91	262.808	<=400	Pass
8DPSK	SISO	HOPP	3DH1	0.385	31.600	318	122.430	<=400	Pass
			3DH3	1.653	31.600	150	247.950	<=400	Pass
			3DH5	2.905	31.600	103	299.215	<=400	Pass

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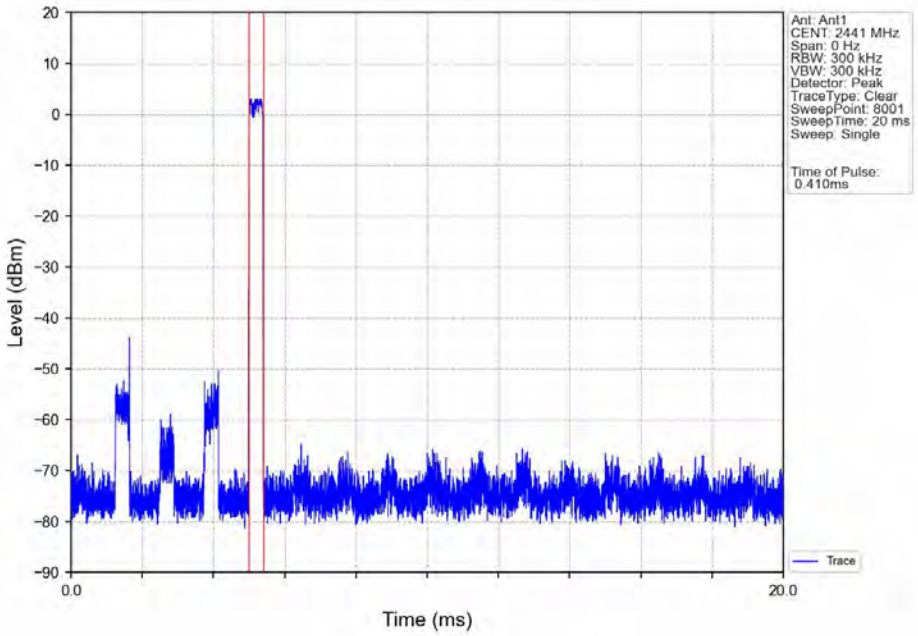
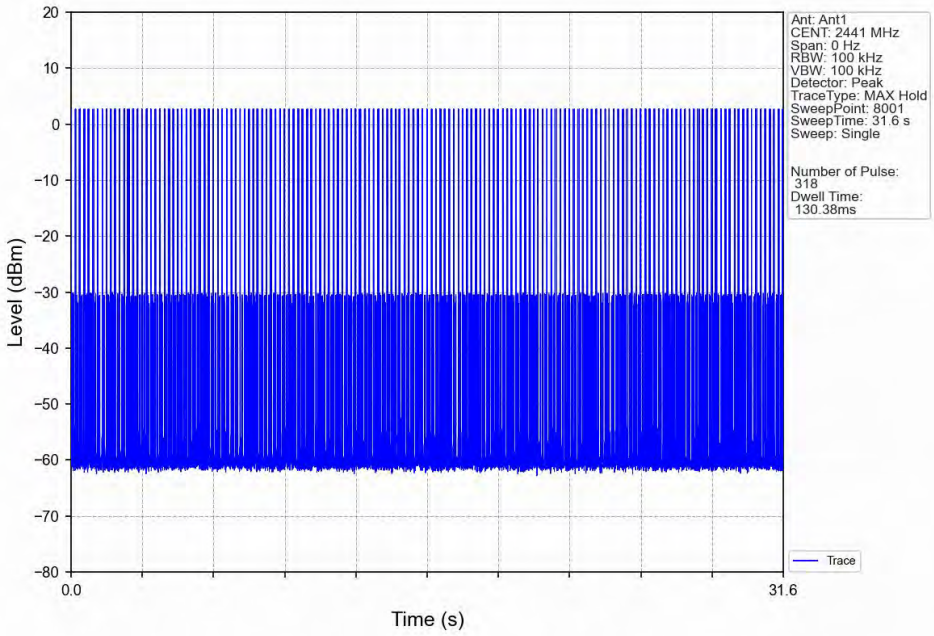
5.2 Test Graph

5.2.1 Ant1

GFSK_DH1_HOPP_Ant1_NTNV



GFSK_DH1_HOPP_Ant1_NTNV



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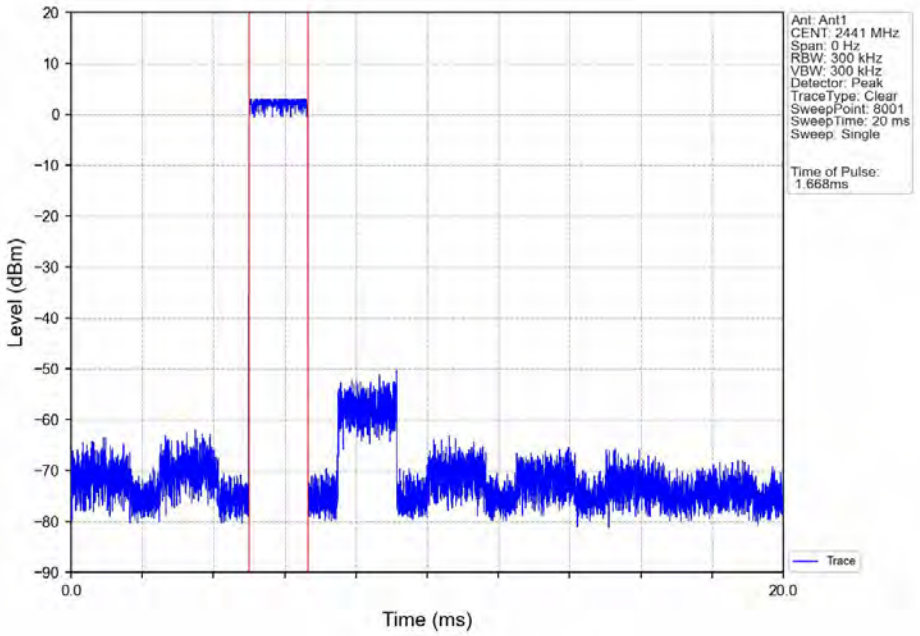
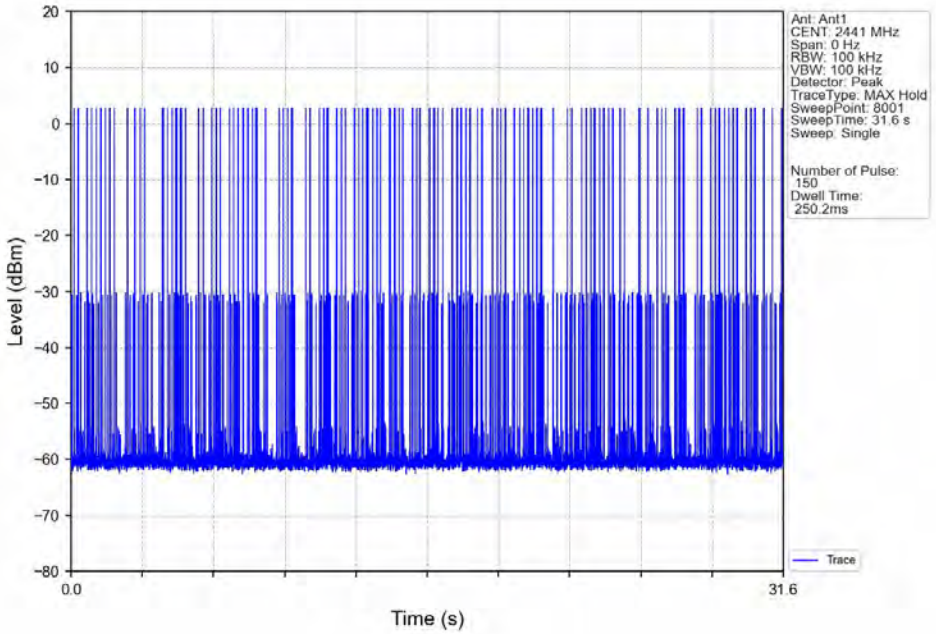
GFSK_DH3_HOPP_Ant1_NTNV



GFSK_DH3_HOPP_Ant1_NTNV



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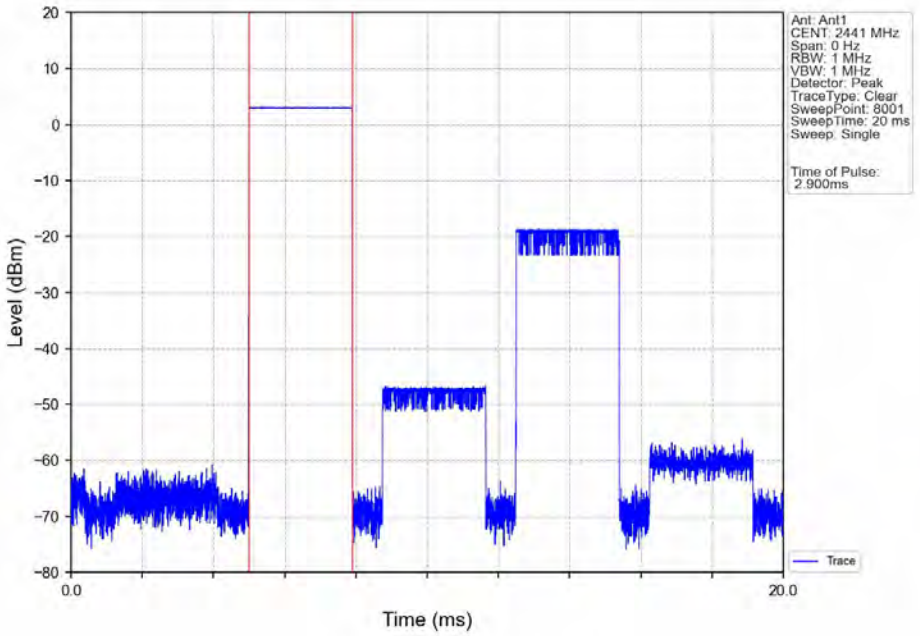
GFSK_DH5_HOPP_Ant1_NTNV



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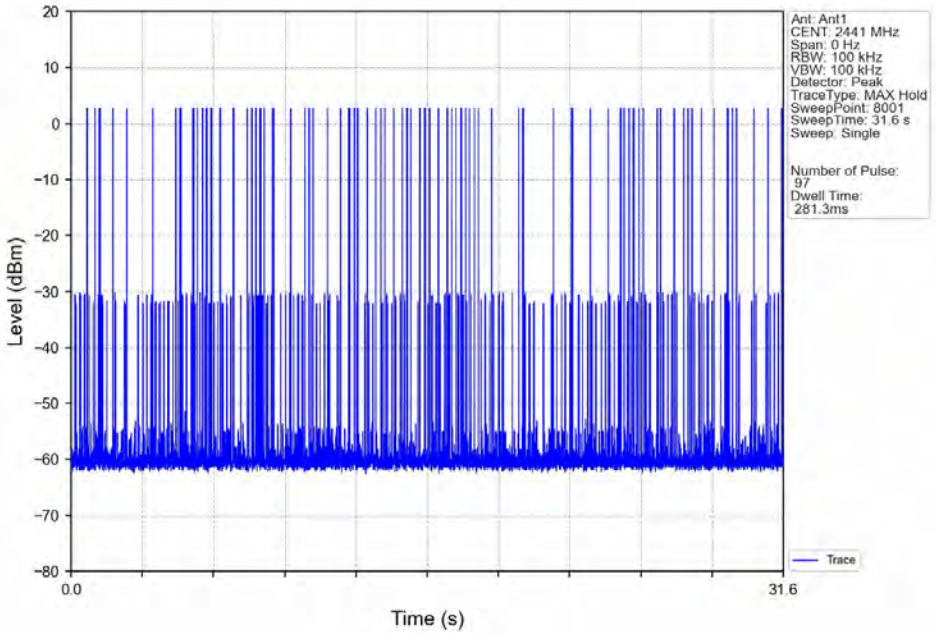

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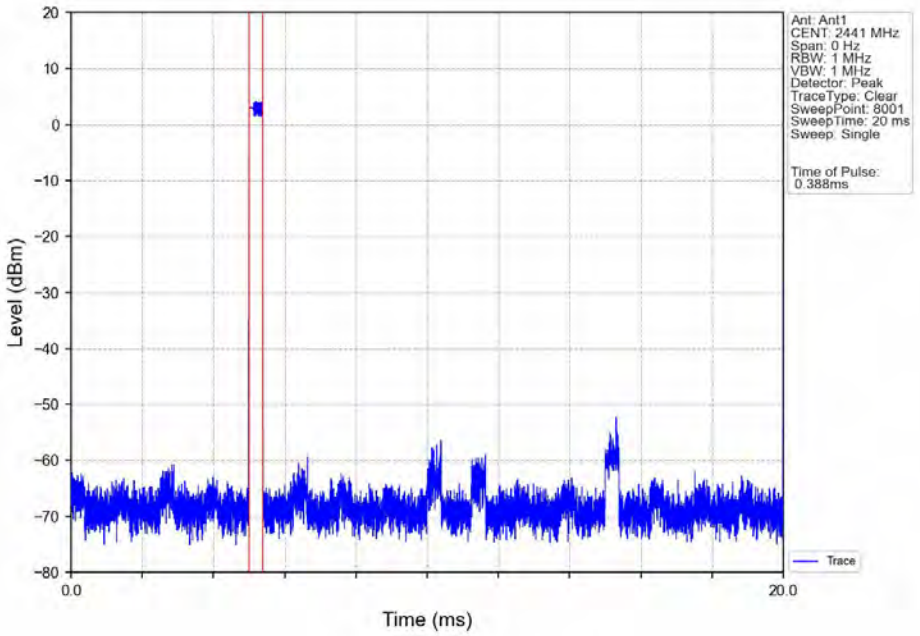
Pi/4DQPSK_2DH1_HOPP_Ant1_NTNV



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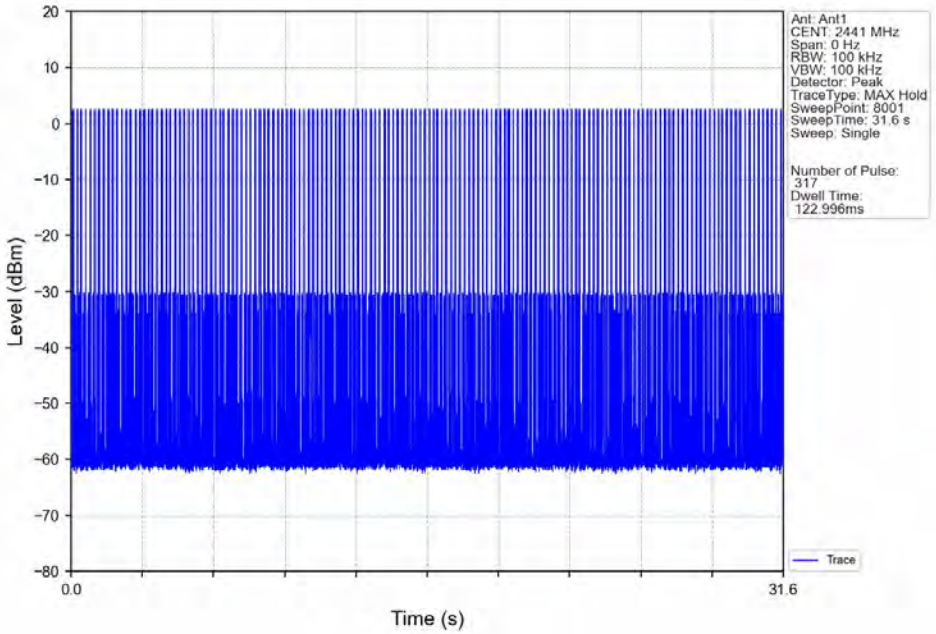

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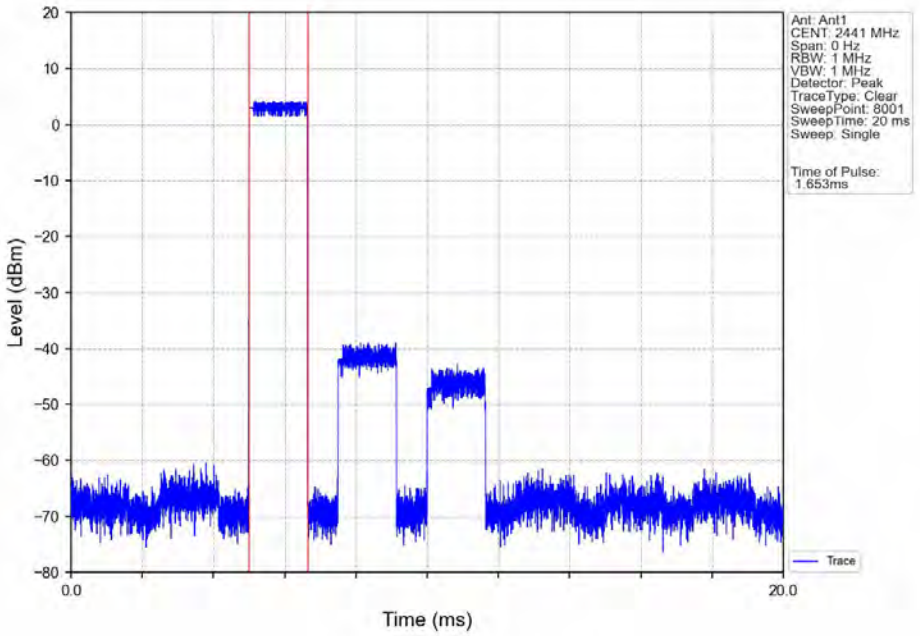
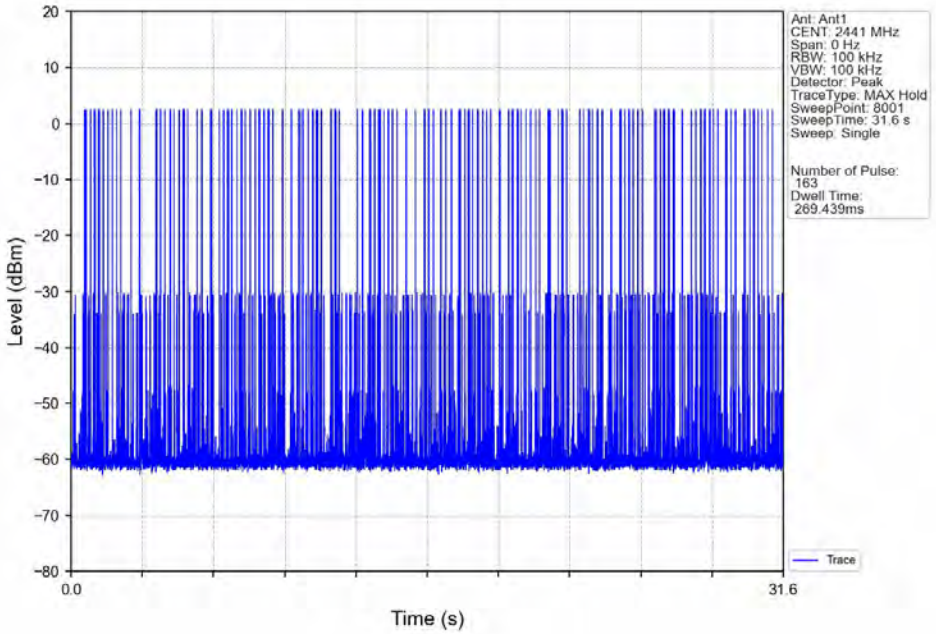
Pi/4DQPSK_2DH3_HOPP_Ant1_NTNV



Pi/4DQPSK_2DH3_HOPP_Ant1_NTNV



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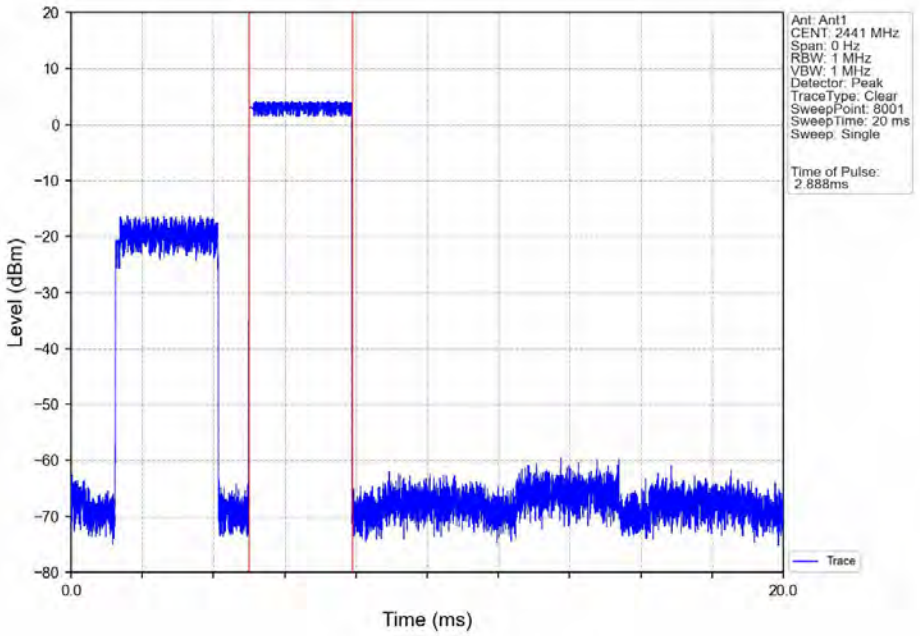
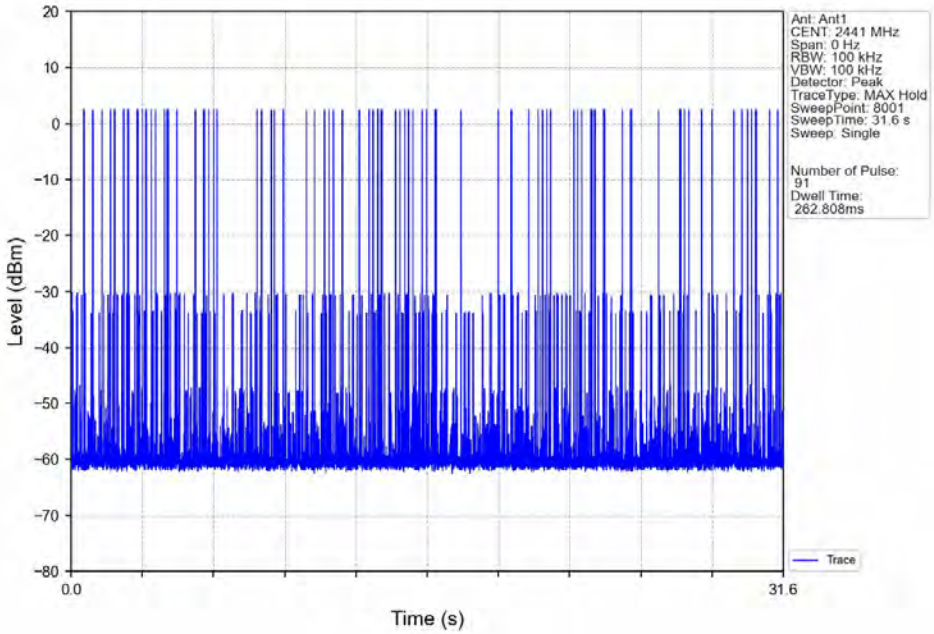
Pi/4DQPSK_2DH5_HOPP_Ant1_NTNV



Pi/4DQPSK_2DH5_HOPP_Ant1_NTNV



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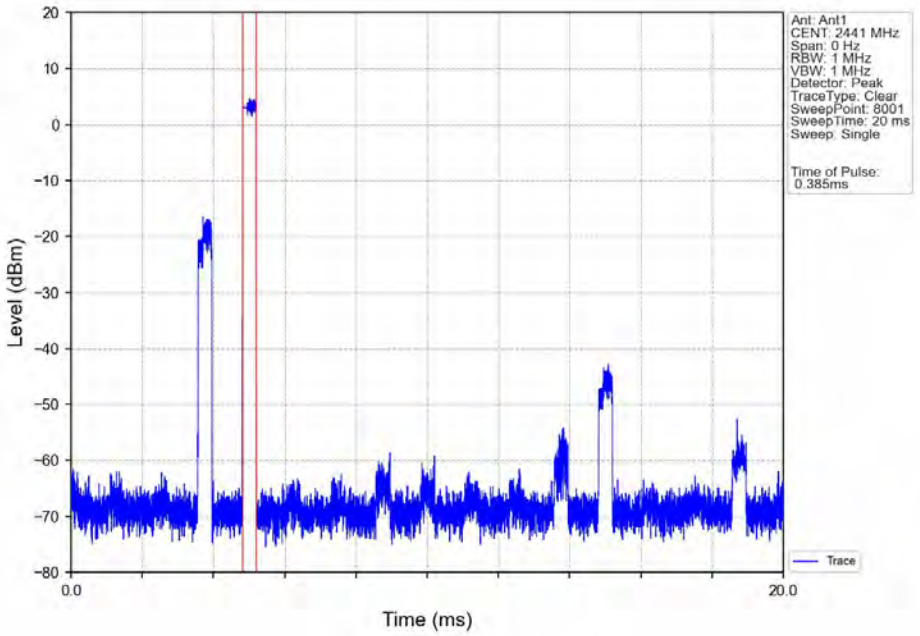
8DPSK_3DH1_HOPP_Ant1_NTNV



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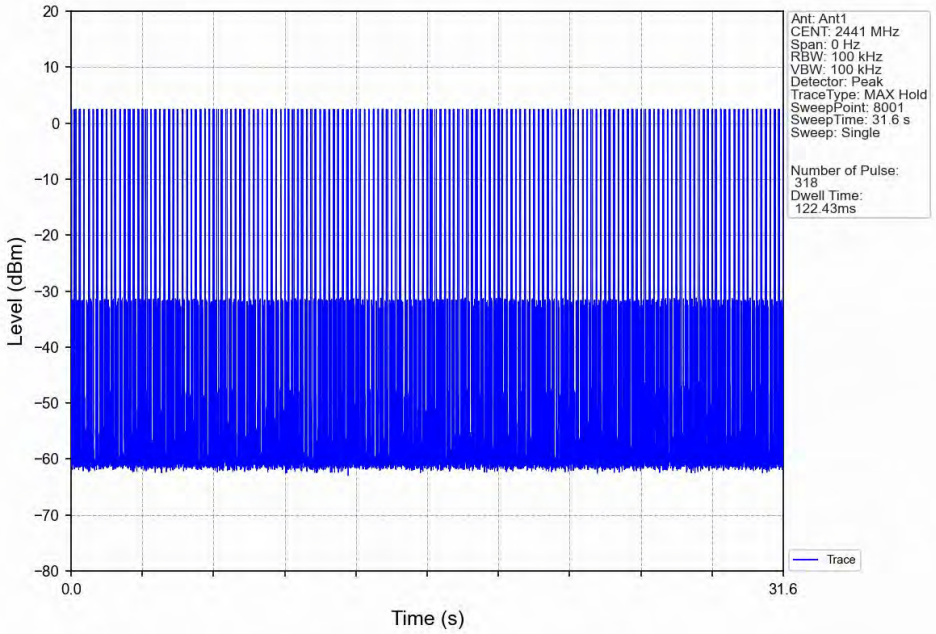

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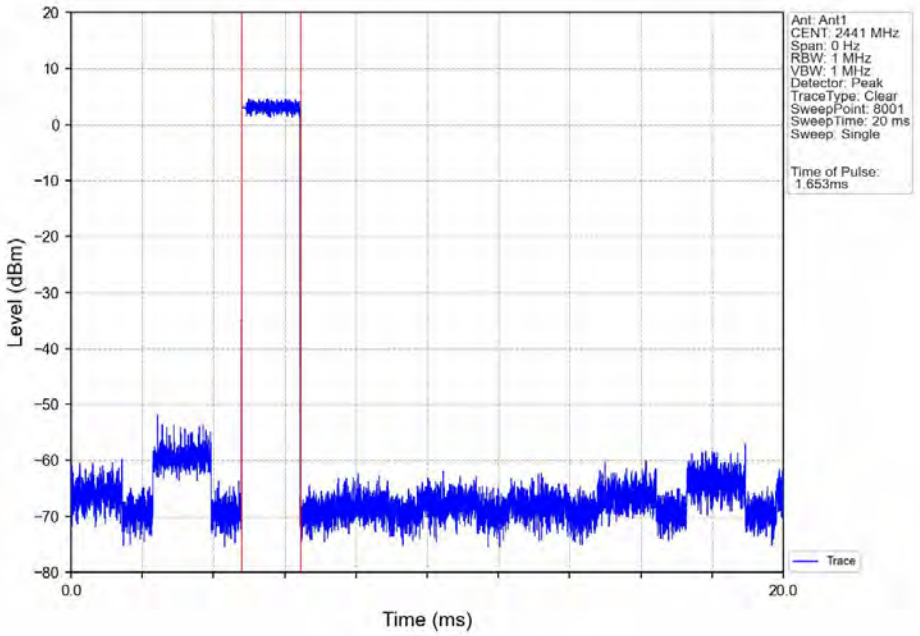
8DPSK_3DH3_HOPP_Ant1_NTNV



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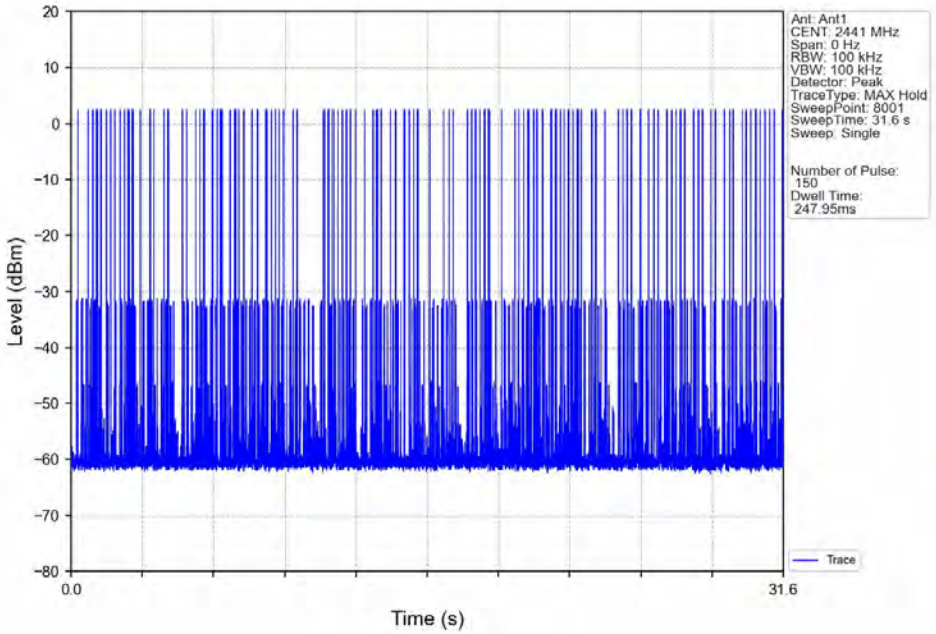

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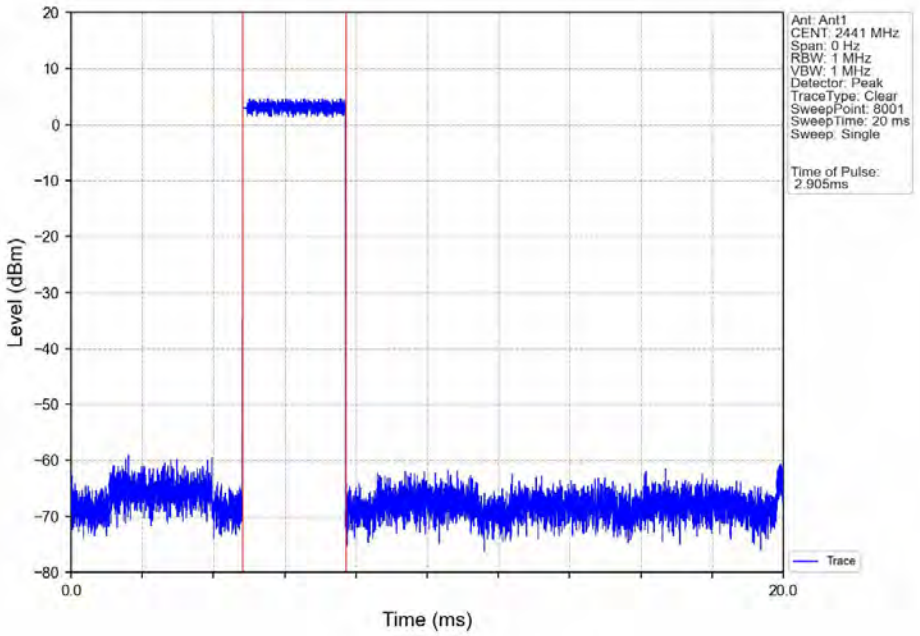
8DPSK_3DH5_HOPP_Ant1_NTNV



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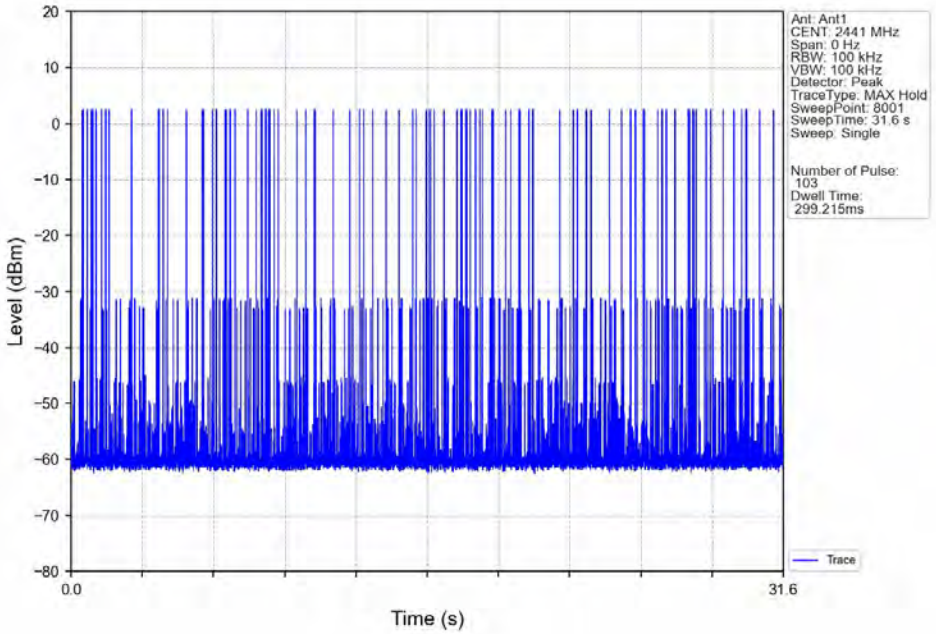

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6. Unwanted Emissions In Non-restricted Frequency Bands

6.1 Test Result

6.1.1 Ref

Mode	TX Type	Frequency (MHz)	Packet Type	ANT	Level of Reference (dBm)
GFSK	SISO	2402	DH5	1	1.51
		2441	DH5	1	3.46
		2480	DH5	1	4.34
Pi/4DQPSK	SISO	2402	2DH5	1	1.35
		2441	2DH5	1	3.34
		2480	2DH5	1	3.83
8DPSK	SISO	2402	3DH5	1	1.54
		2441	3DH5	1	3.53
		2480	3DH5	1	4.34
Note1: Refer to FCC Part 15.247 (d) and ANSI C63.10-2013, the channel contains the maximum PSD level was used to establish the reference level.					

6.1.2 CSE

Mode	TX Type	Frequency (MHz)	Packet Type	ANT	Level of Reference (dBm)	Limit (dBm)	Verdict
GFSK	SISO	2402	DH5	1	4.34	-15.66	Pass
		2441	DH5	1	4.34	-15.66	Pass
		2480	DH5	1	4.34	-15.66	Pass
		HOPP	DH5	1	4.34	-15.66	Pass
					4.34	-15.66	Pass
Pi/4DQPSK	SISO	2402	2DH5	1	3.83	-16.17	Pass
		2441	2DH5	1	3.83	-16.17	Pass
		2480	2DH5	1	3.83	-16.17	Pass
		HOPP	2DH5	1	3.83	-16.17	Pass
					3.83	-16.17	Pass
8DPSK	SISO	2402	3DH5	1	4.34	-15.66	Pass
		2441	3DH5	1	4.34	-15.66	Pass
		2480	3DH5	1	4.34	-15.66	Pass
		HOPP	3DH5	1	4.34	-15.66	Pass
					4.34	-15.66	Pass
Note1: Refer to FCC Part 15.247 (d) and ANSI C63.10-2013, the channel contains the maximum PSD level was used to establish the reference level.							

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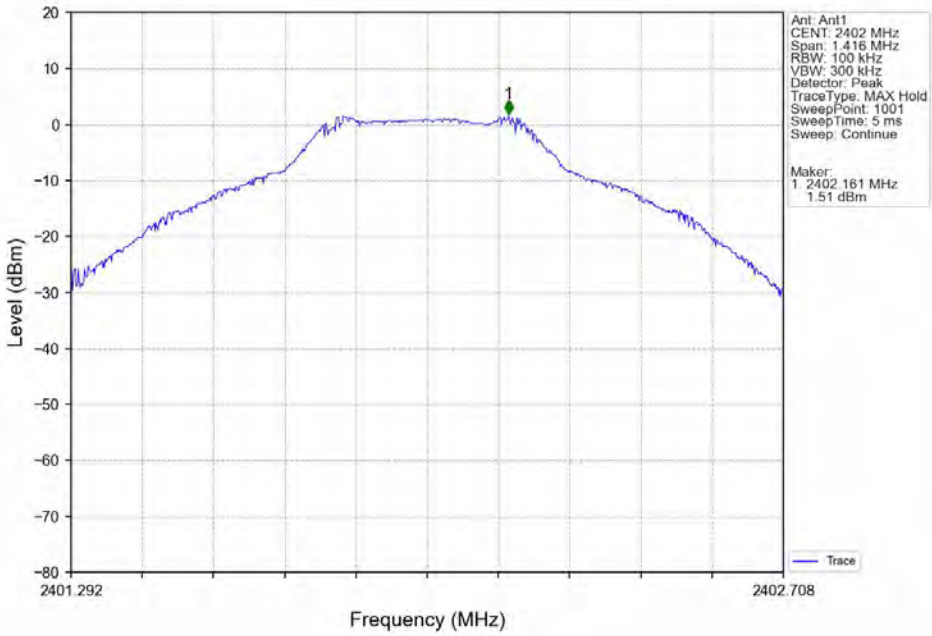
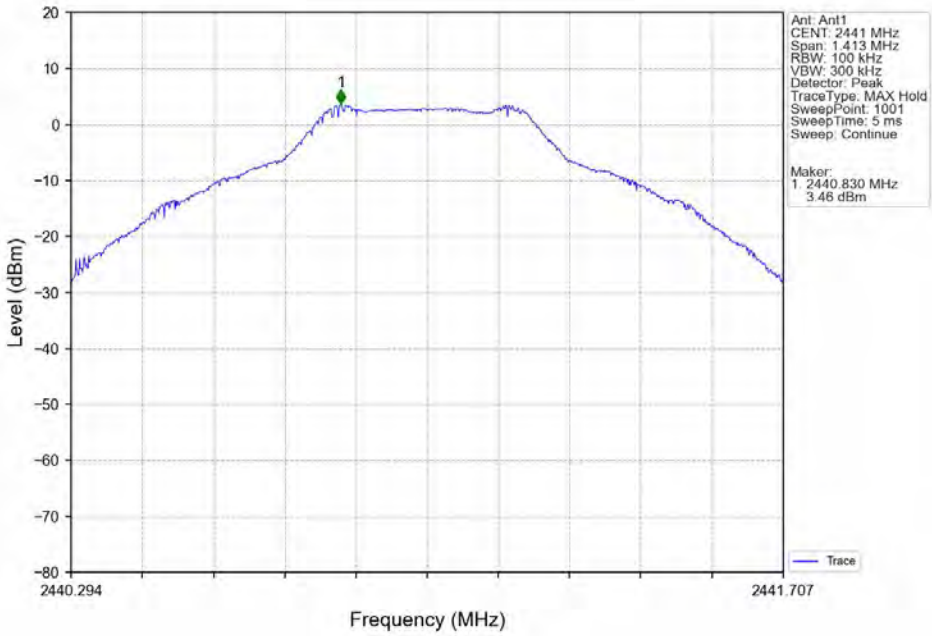
6.2 Test Graph

6.2.1 Ref

GFSK_DH5_LCH_2402MHz_Ant1_NTNV



GFSK_DH5_MCH_2441MHz_Ant1_NTNV



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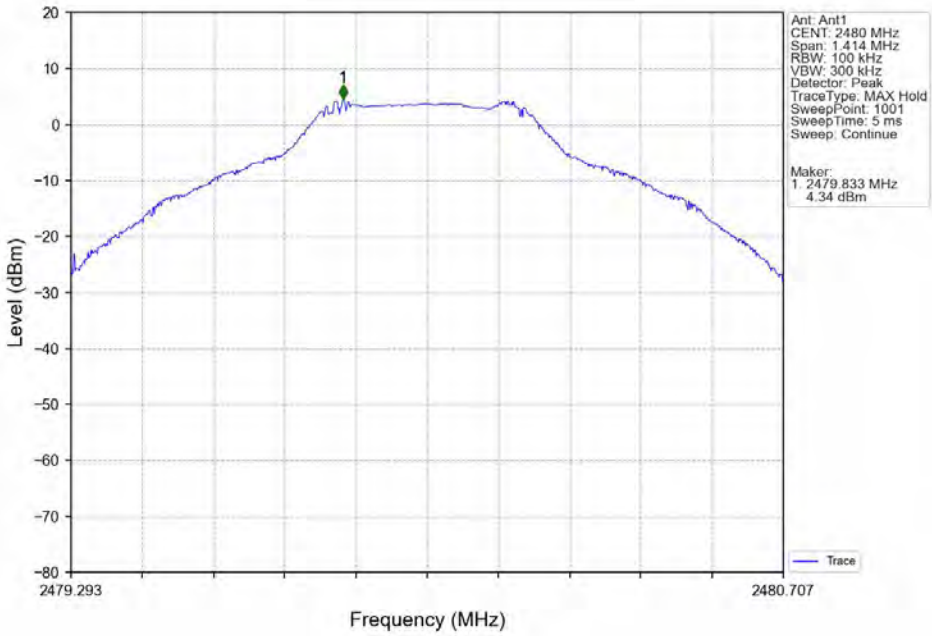
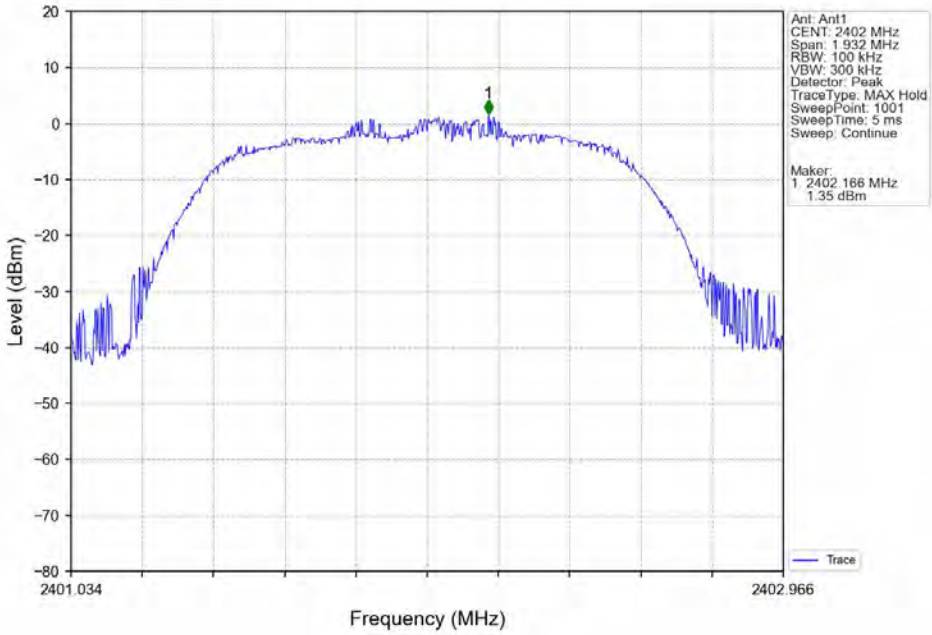
GFSK_DH5_HCH_2480MHz_Ant1_NTNV



Pi/4DQPSK_2DH5_LCH_2402MHz_Ant1_NTNV



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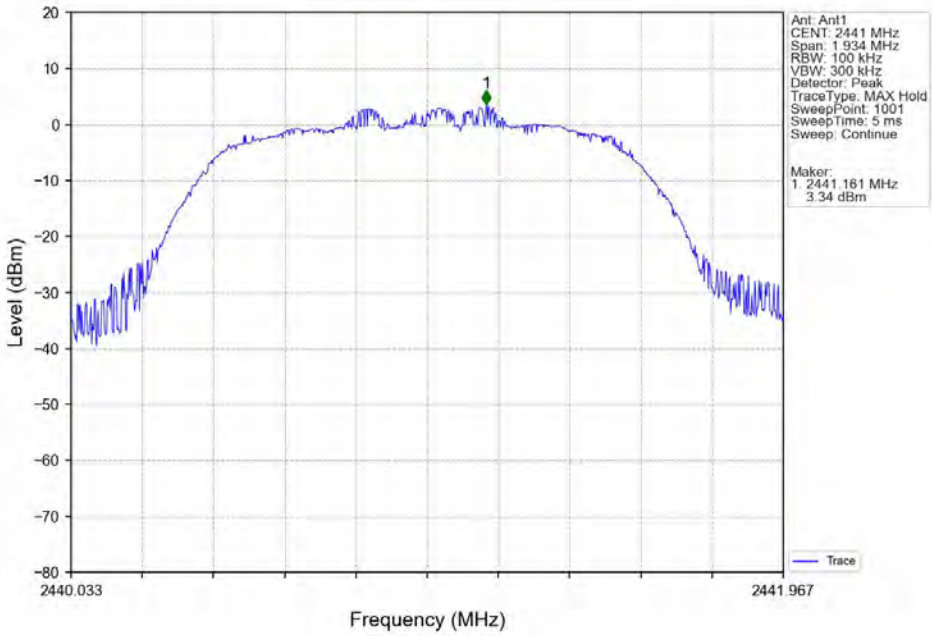
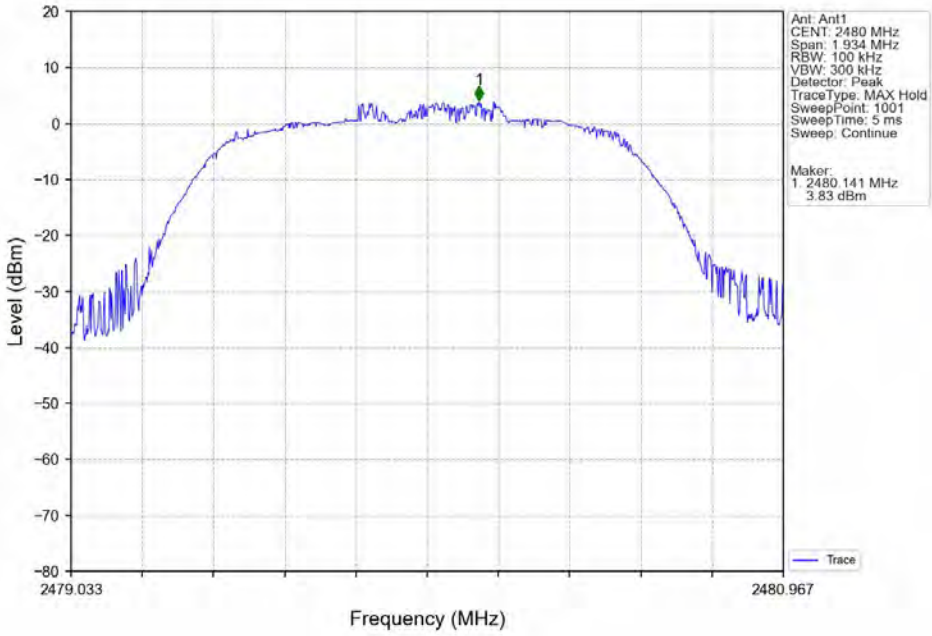
Pi/4DQPSK_2DH5_MCH_2441MHz_Ant1_NTNV



Pi/4DQPSK_2DH5_HCH_2480MHz_Ant1_NTNV



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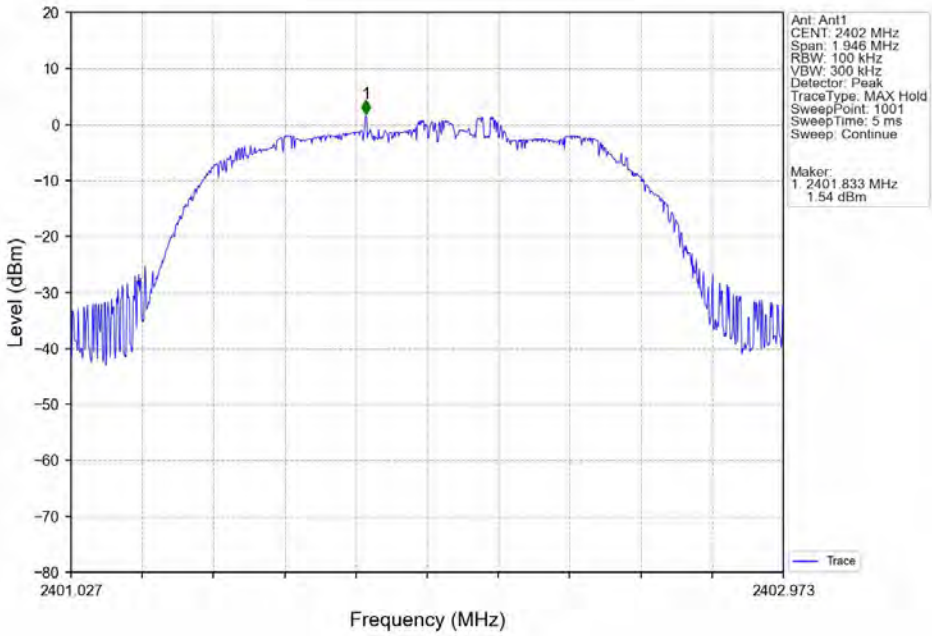
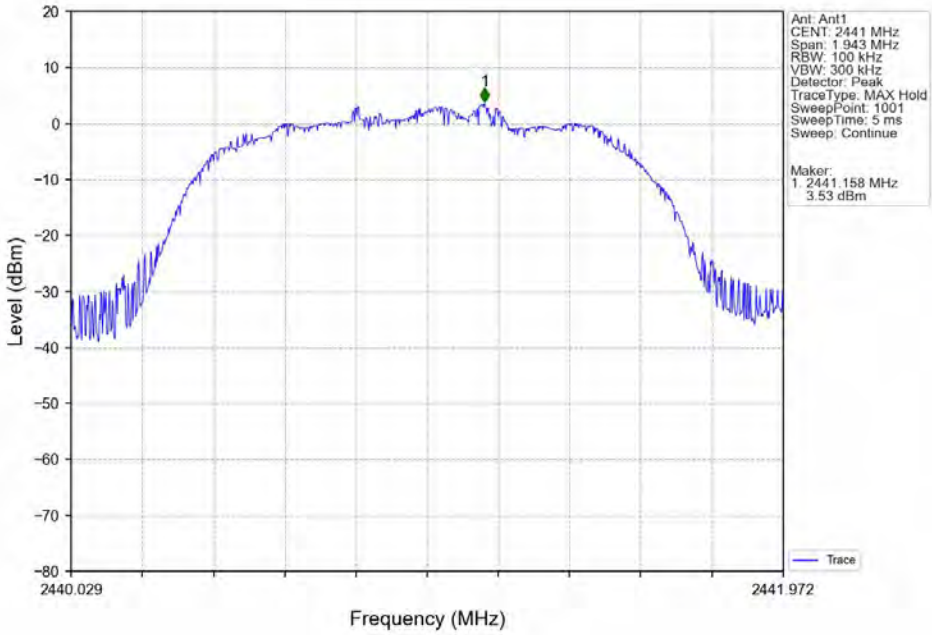
8DPSK_3DH5_LCH_2402MHz_Ant1_NTNV



8DPSK_3DH5_MCH_2441MHz_Ant1_NTNV



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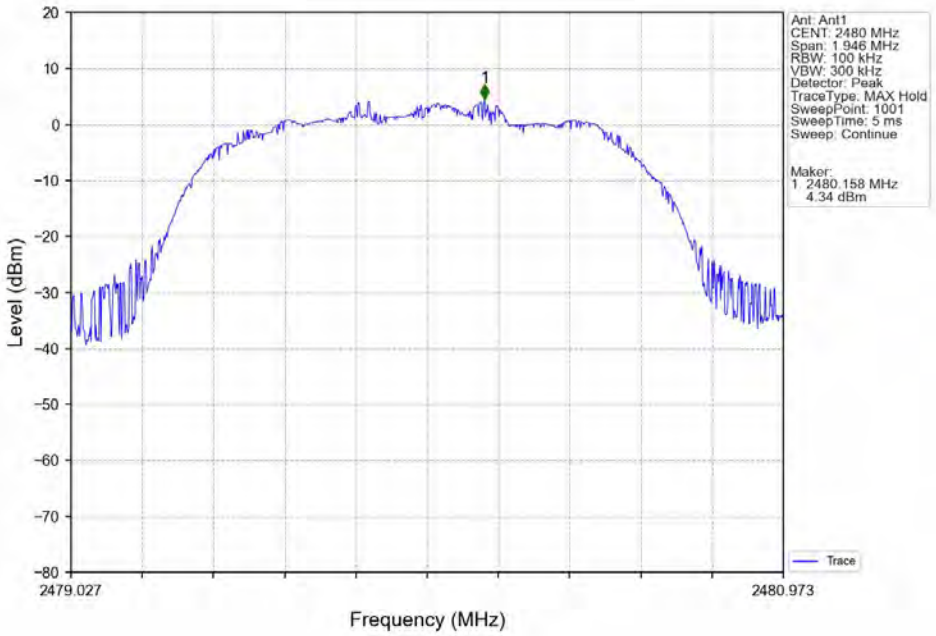
8DPSK_3DH5_HCH_2480MHz_Ant1_NTNV



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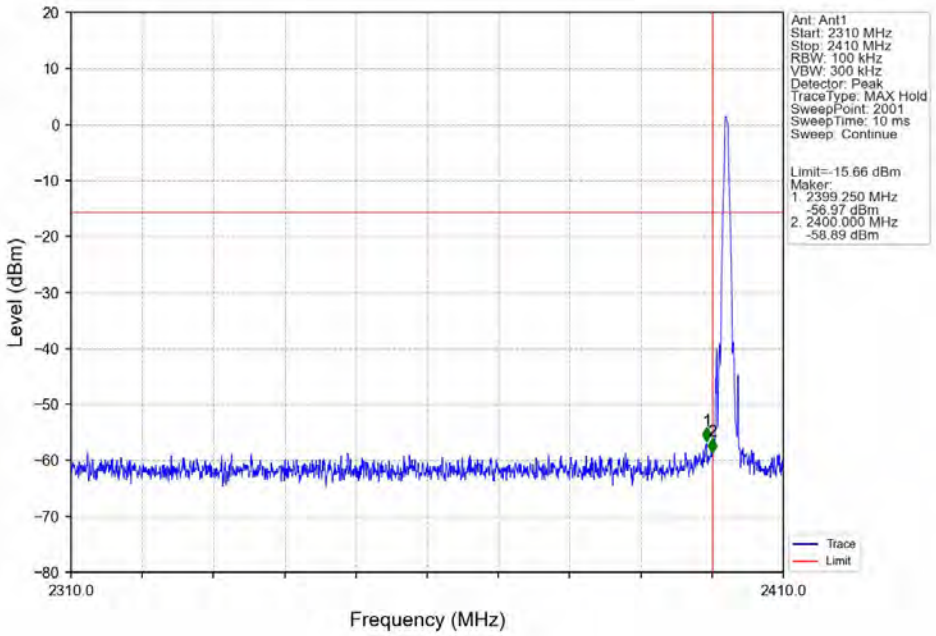
6.2.2 CSE

GFSK_DH5_LCH_2402MHz_Ant1_NTNV



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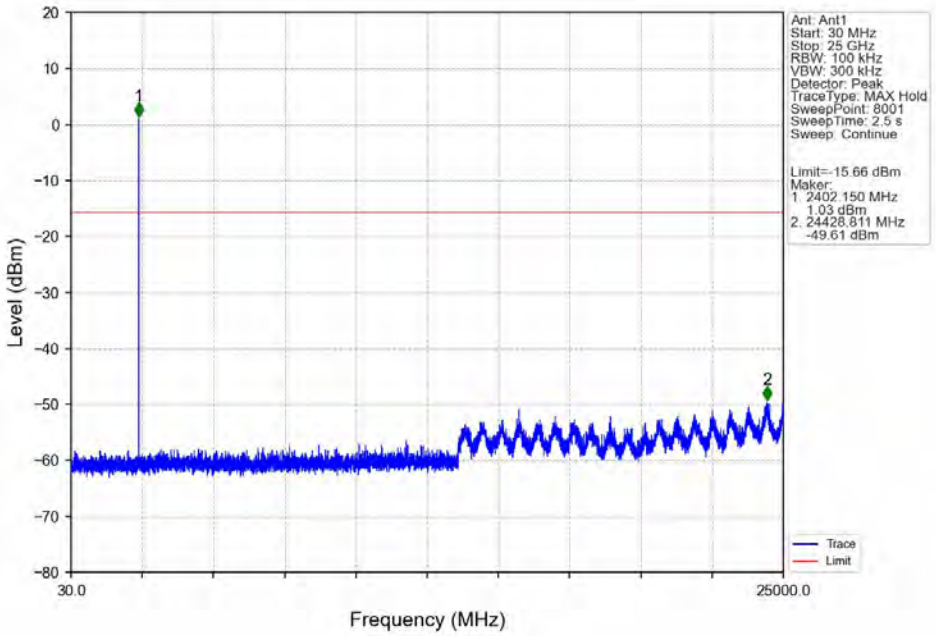

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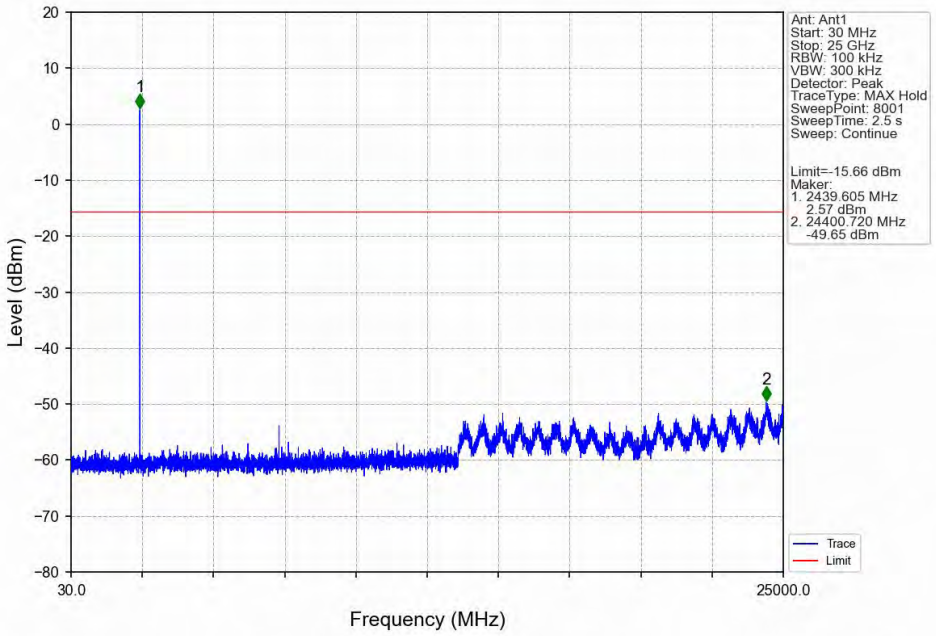
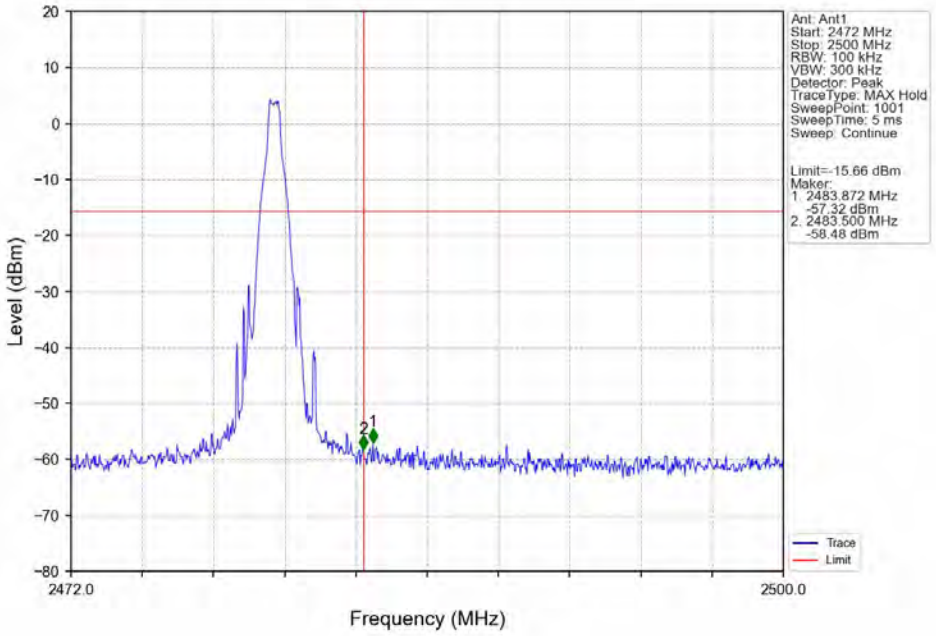
GFSK_DH5_MCH_2441MHz_Ant1_NTNV



GFSK_DH5_HCH_2480MHz_Ant1_NTNV



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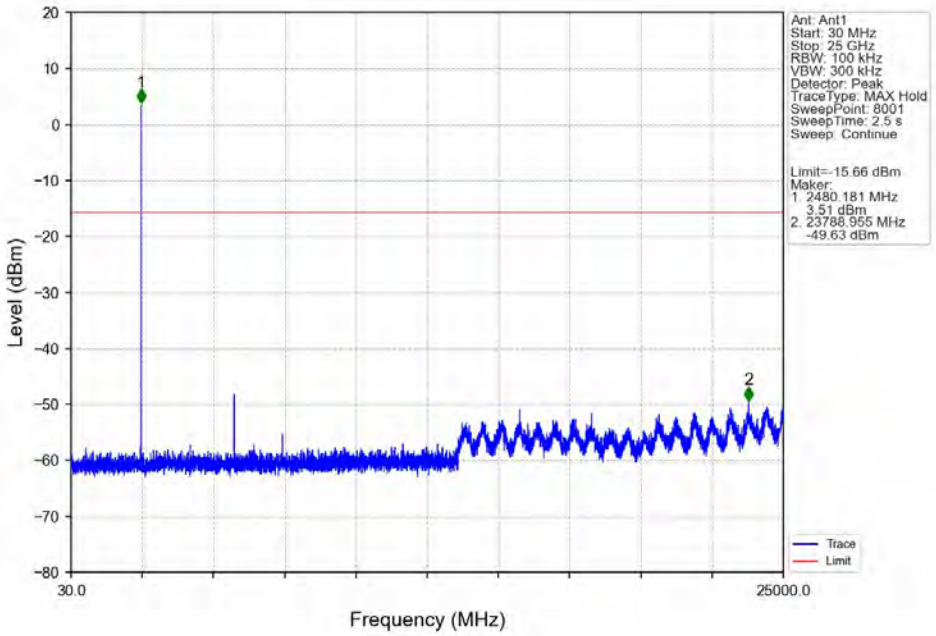
GFSK_DH5_HCH_2480MHz_Ant1_NTNV



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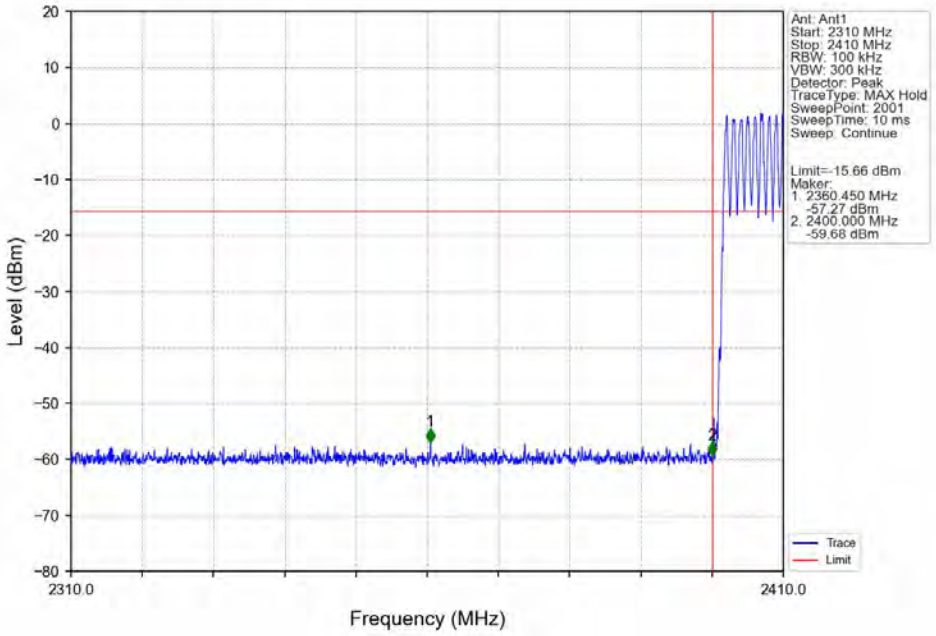

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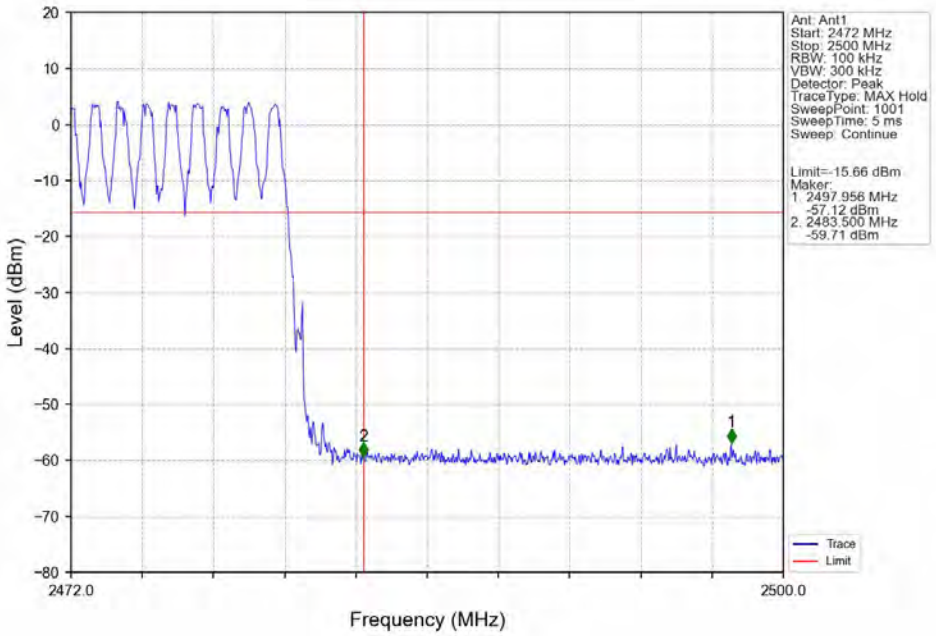
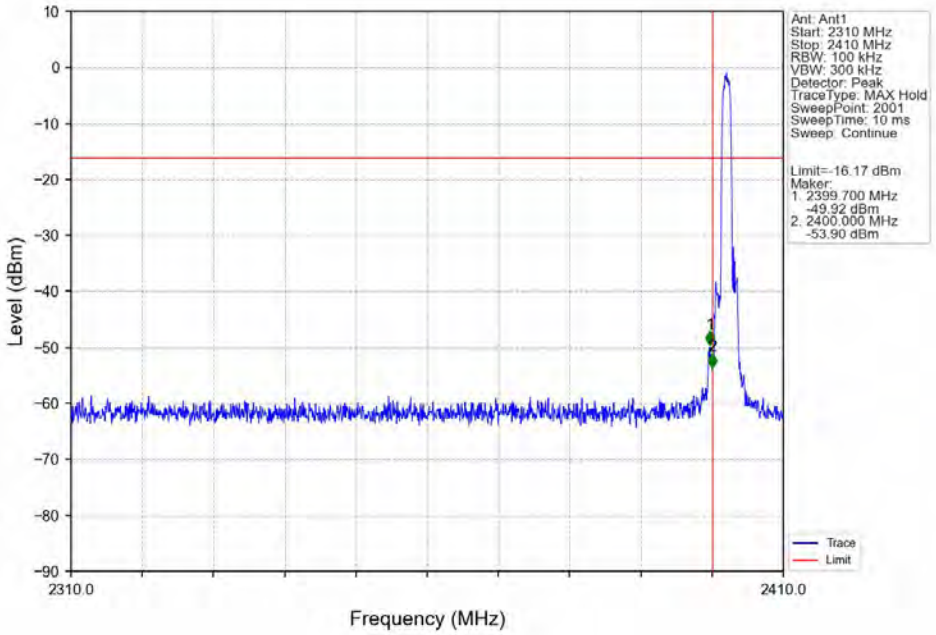
GFSK_DH5_HOPP_Ant1_NTNV



Pi/4DQPSK_2DH5_LCH_2402MHz_Ant1_NTNV



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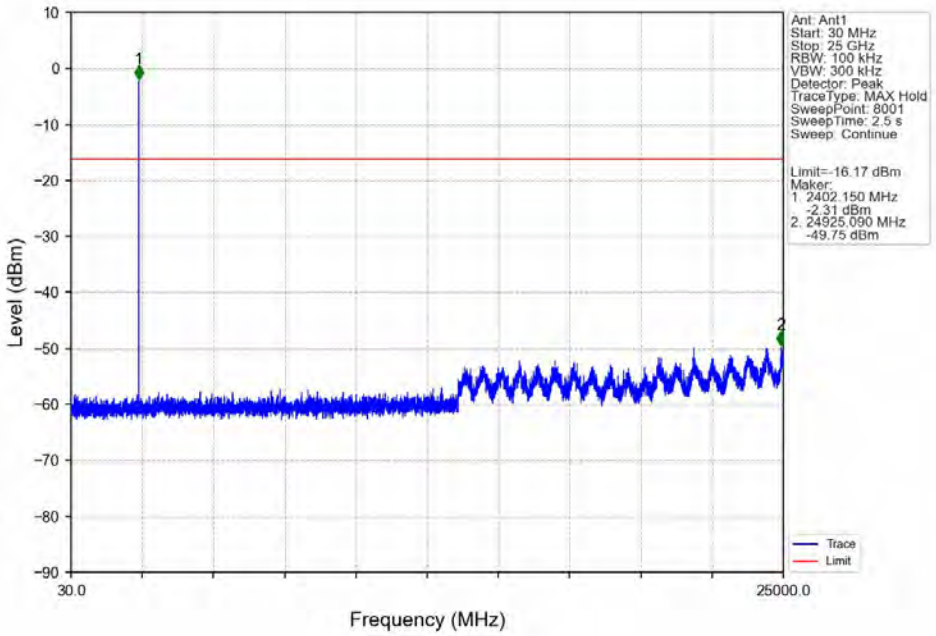
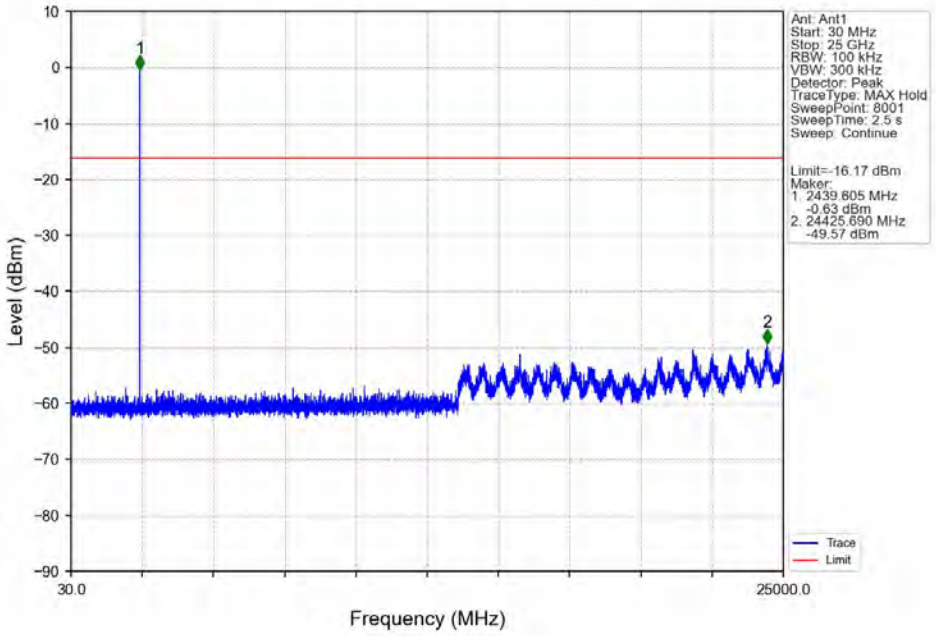
Pi/4DQPSK_2DH5_LCH_2402MHz_Ant1_NTNV



Pi/4DQPSK_2DH5_MCH_2441MHz_Ant1_NTNV



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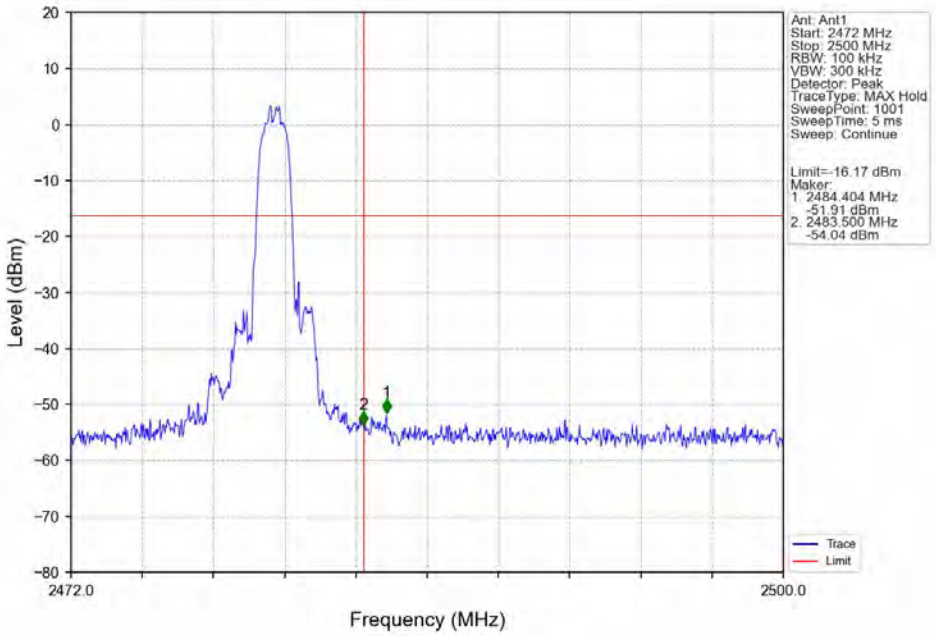
Pi/4DQPSK_2DH5_HCH_2480MHz_Ant1_NTNV



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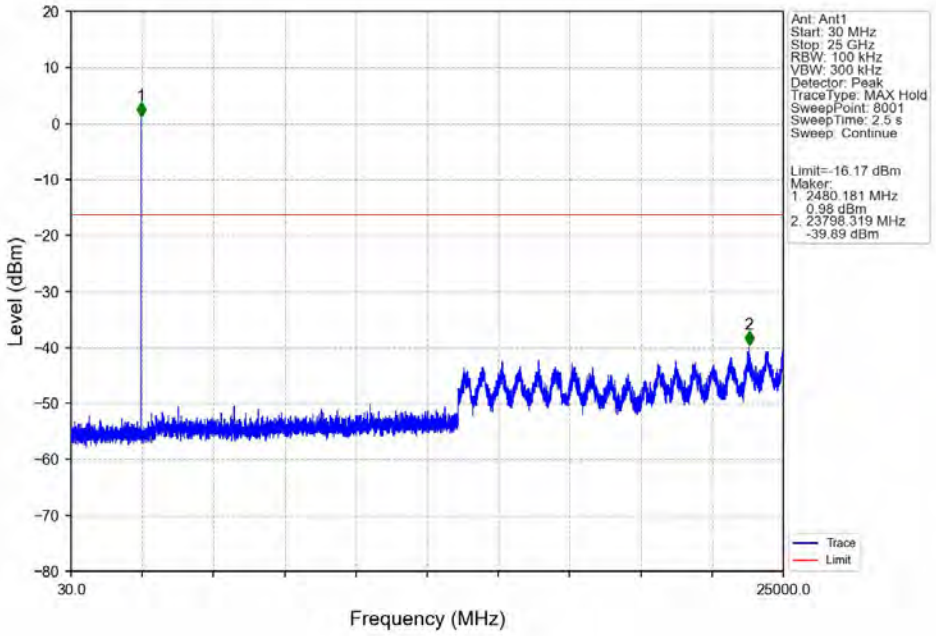

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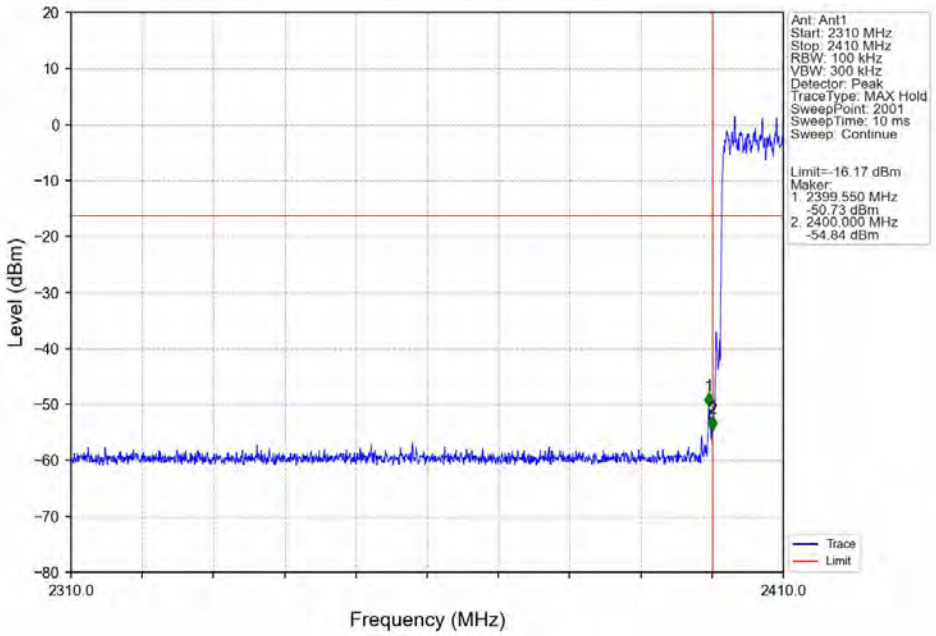
Pi/4DQPSK_2DH5_HOPP_Ant1_NTNV



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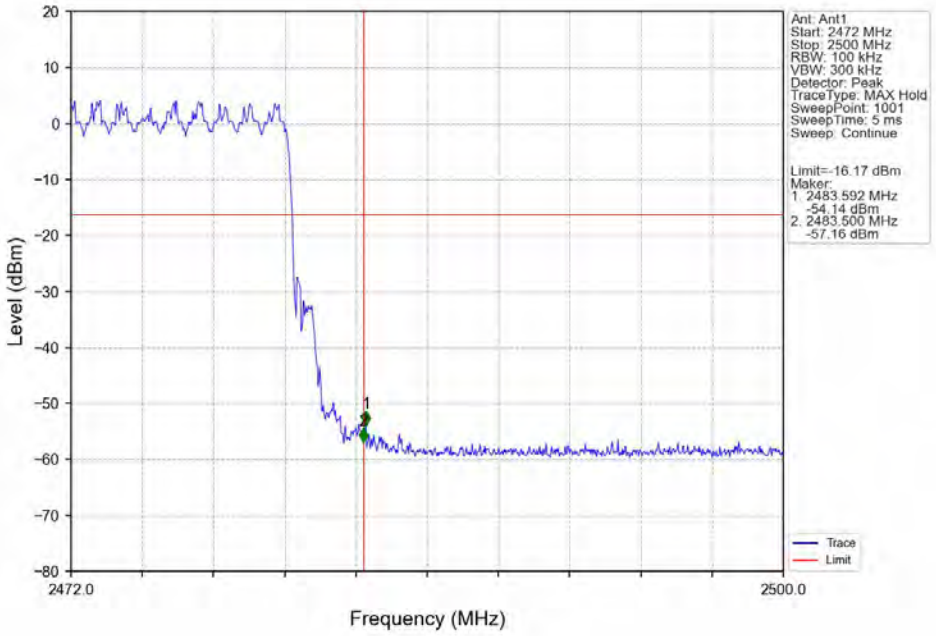

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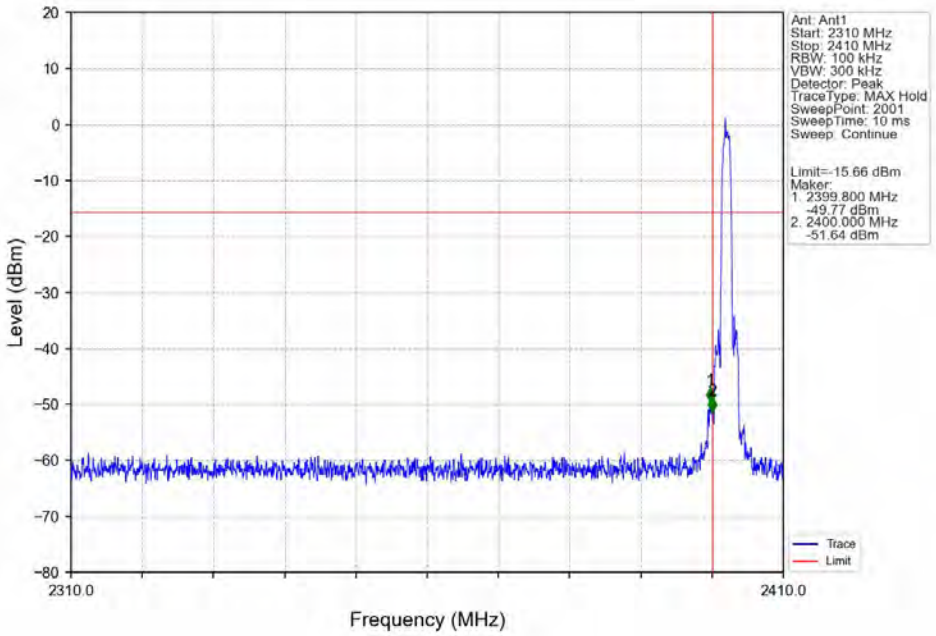
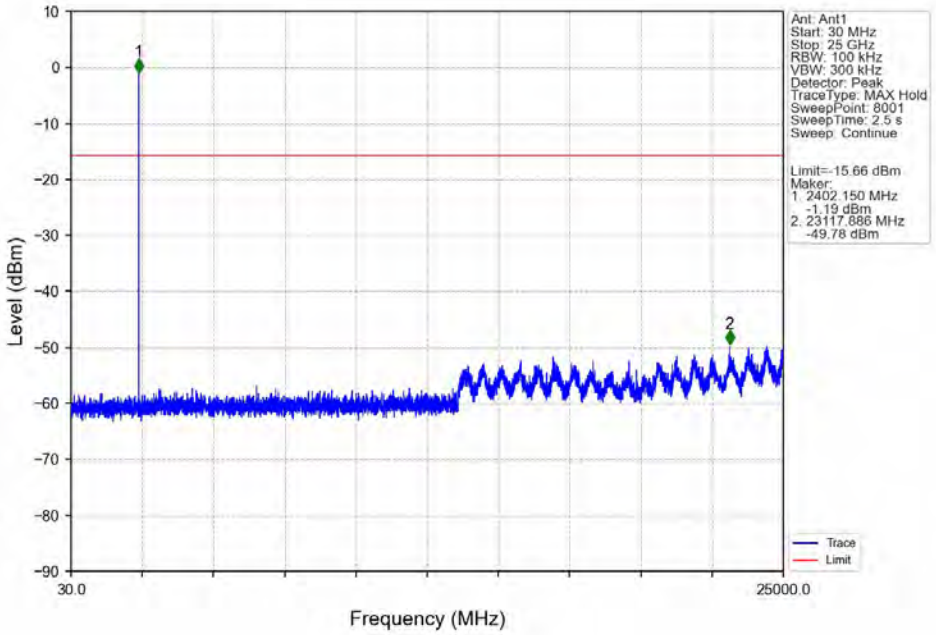
8DPSK_3DH5_LCH_2402MHz_Ant1_NTNV



8DPSK_3DH5_LCH_2402MHz_Ant1_NTNV



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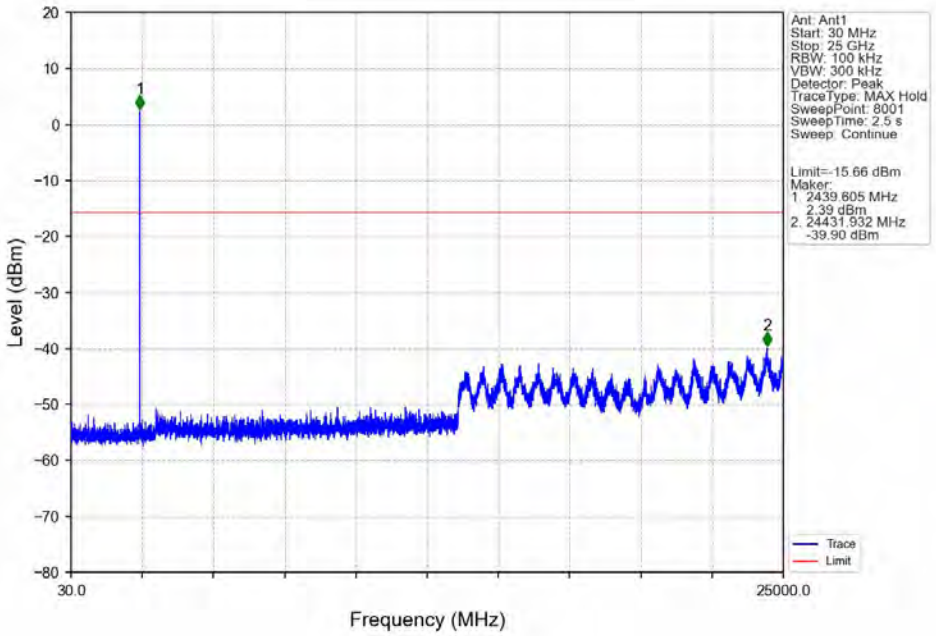
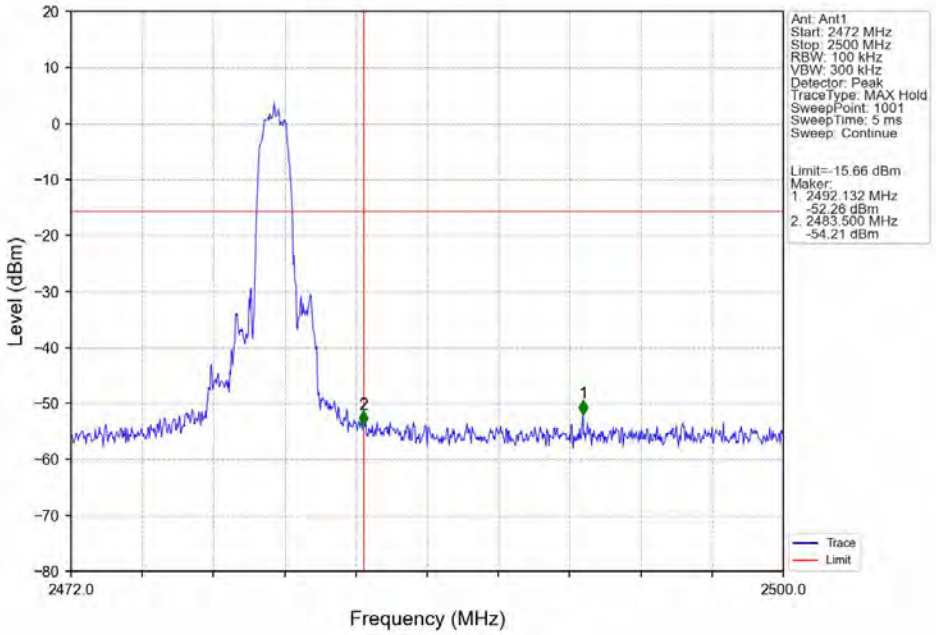
8DPSK_3DH5_MCH_2441MHz_Ant1_NTNV



8DPSK_3DH5_HCH_2480MHz_Ant1_NTNV



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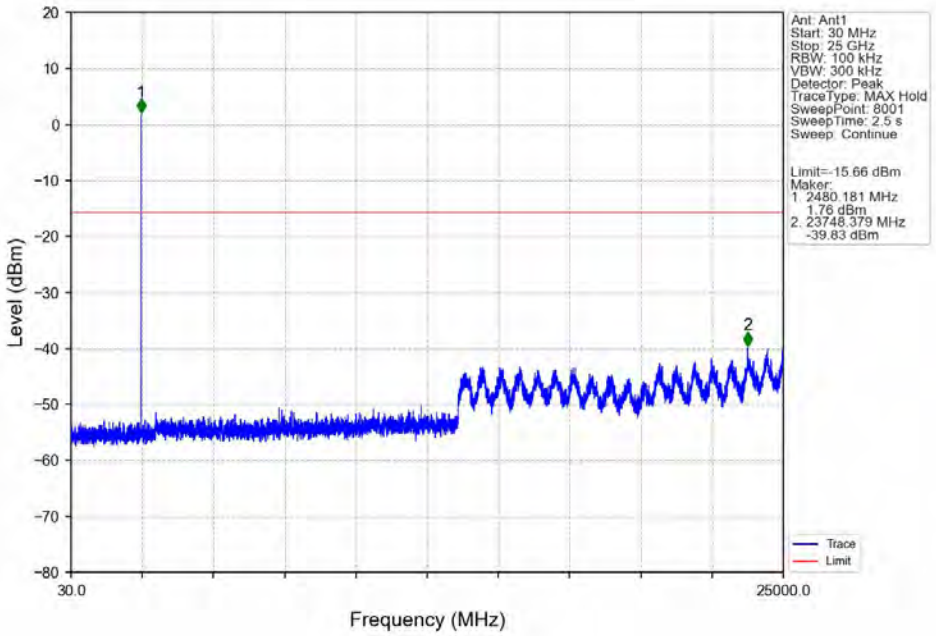
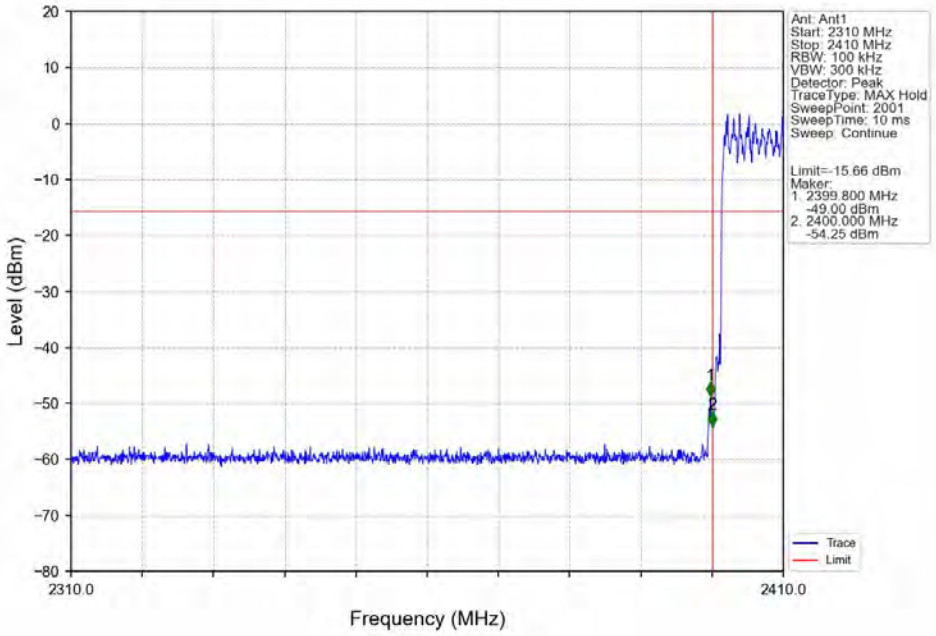
8DPSK_3DH5_HCH_2480MHz_Ant1_NTNV



8DPSK_3DH5_HOPP_Ant1_NTNV



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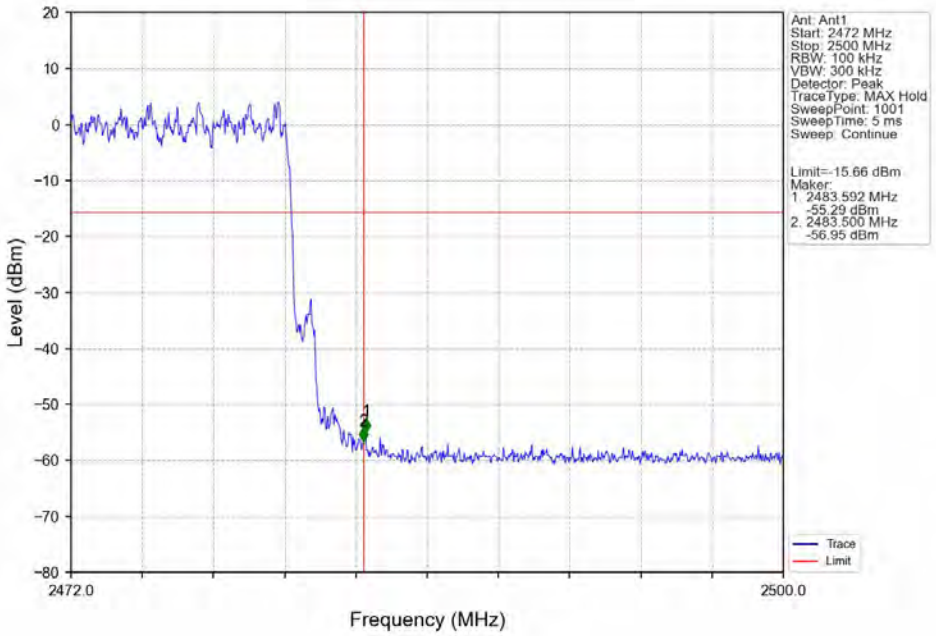
8DPSK_3DH5_HOPP_Ant1_NTNV



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7. Form731

7.1 Test Result

7.1.1 Form731

Lower Freq (MHz)	High Freq (MHz)	MAX Power (W)	MAX Power (dBm)
2402	2480	0.0044	6.45

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